

Capacity and Beyond

Erozan M. Kurtas

Seagate

We turn on ideas



Acknowledgement

M. Fatih Erden

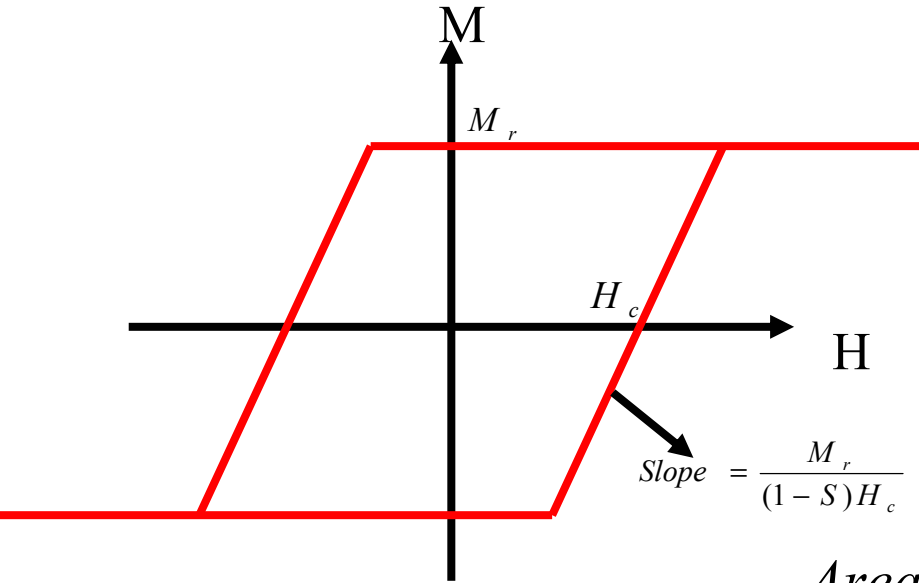
Sami Iren

Dieter Arnold

Raman Venkataramani

Inci Ozgunes

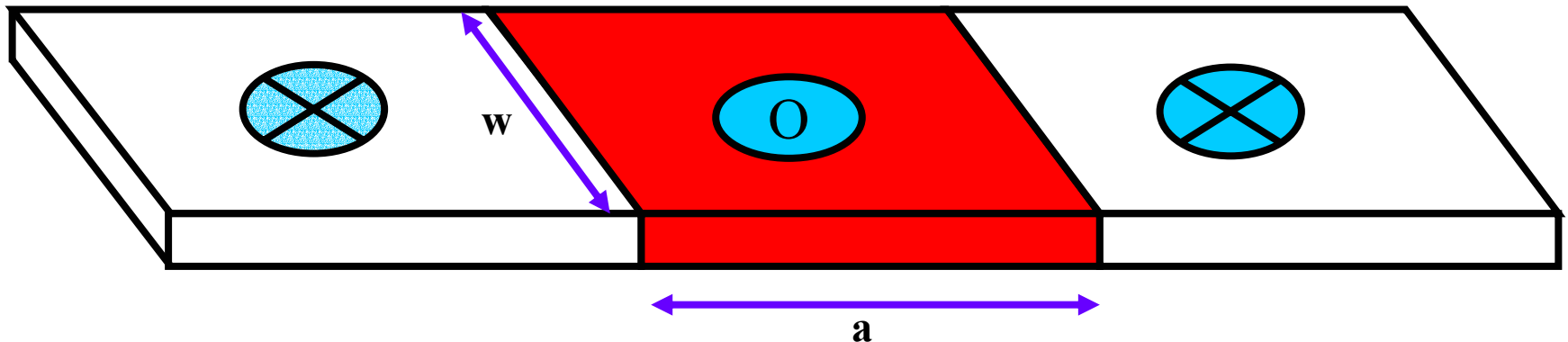
Conventional system



Store bit by

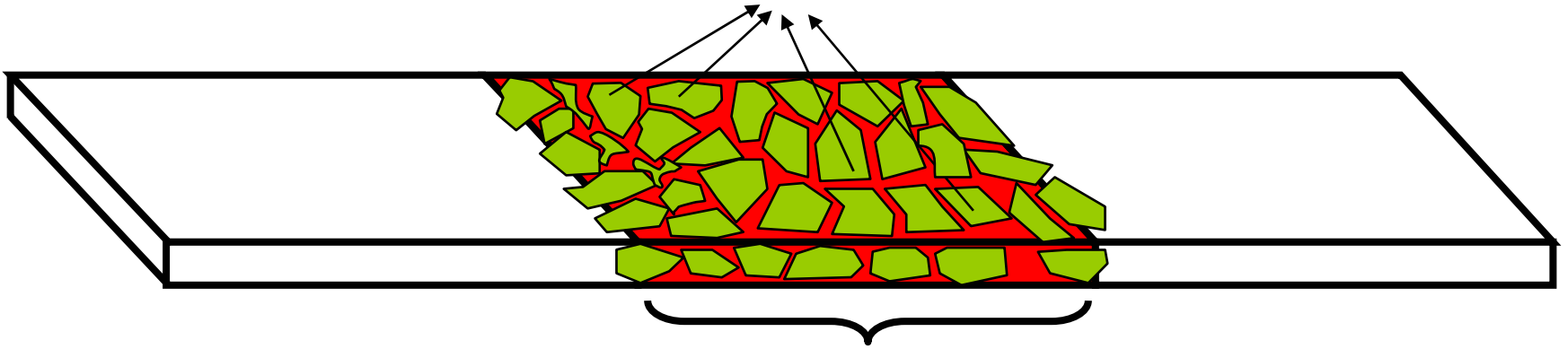
- Applying external $H > H_c$ (magnetize up)
- Applying external $H < -H_c$ (magnetize down)

$$\text{ArealDensity}[\text{bits} / \text{inch}^2] = \frac{1[\text{bit}]}{a[\text{inch}]w[\text{inch}]}$$



In reality there are tiny grains

Tiny grains with finite volume V and anisotropy coefficient K_u



Minimum grain number fixed to preserve SNR

Maximum value limited by maximum writer field

Maximum Attainable
Areal Density is Limited

Super paramagnetic limit :

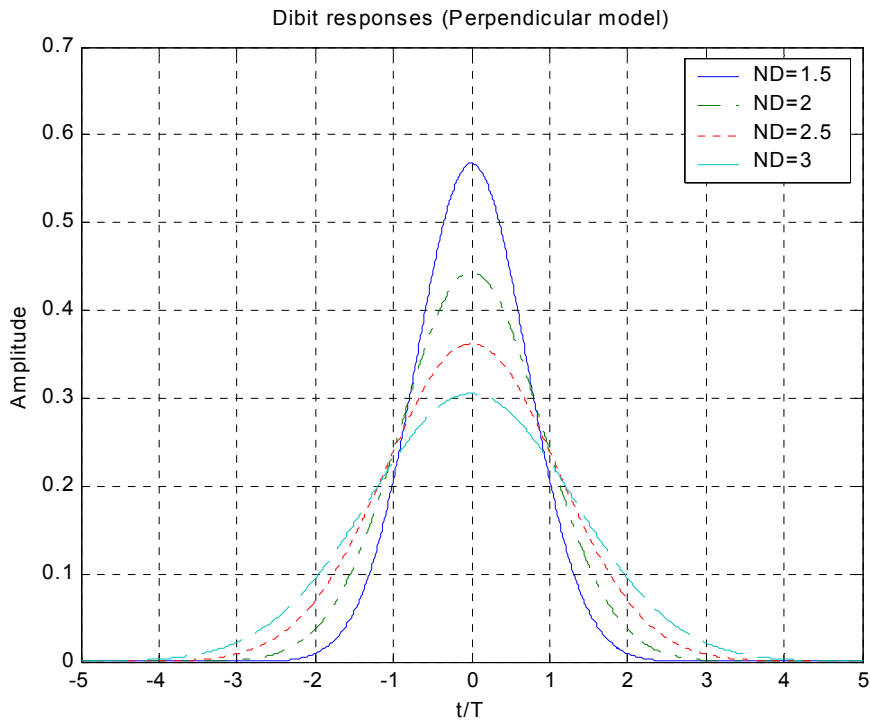
$$\frac{K_u V}{k_B T} \geq M$$

Boltzmann Constant

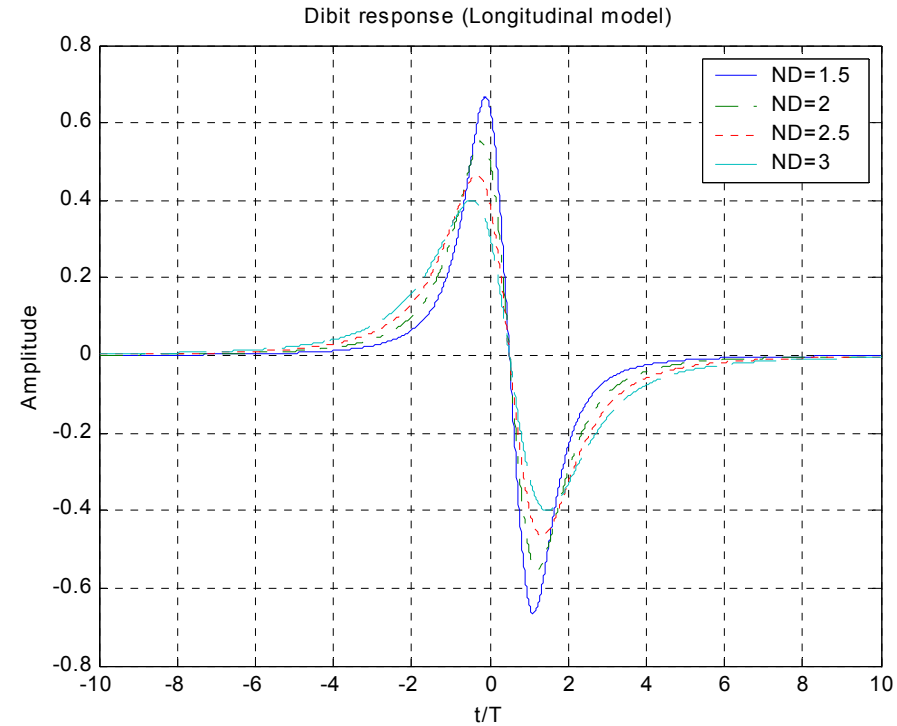
Temperature

Large number, like 60

Dibit Responses Compared



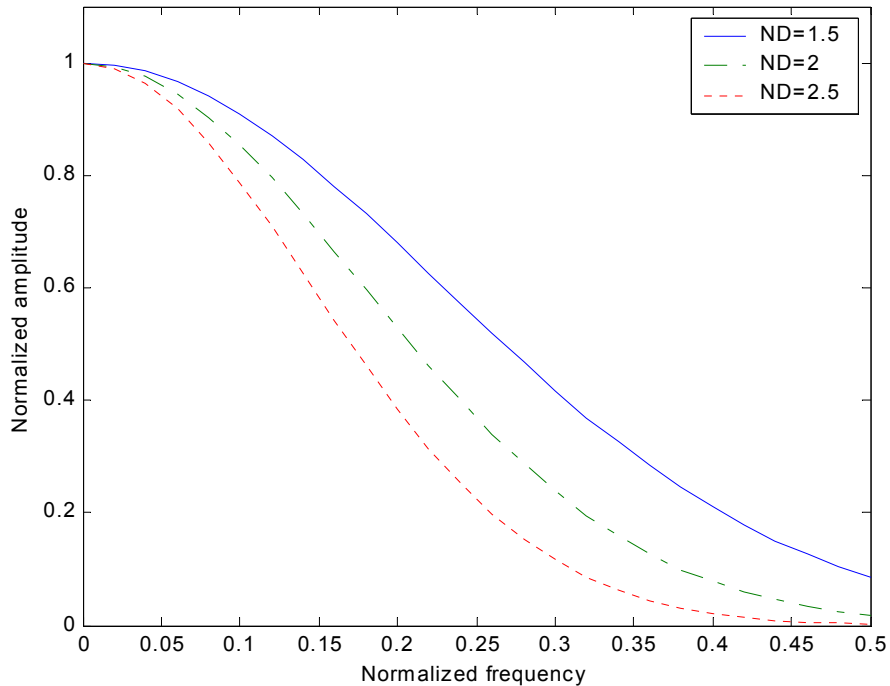
Perpendicular model



Longitudinal model

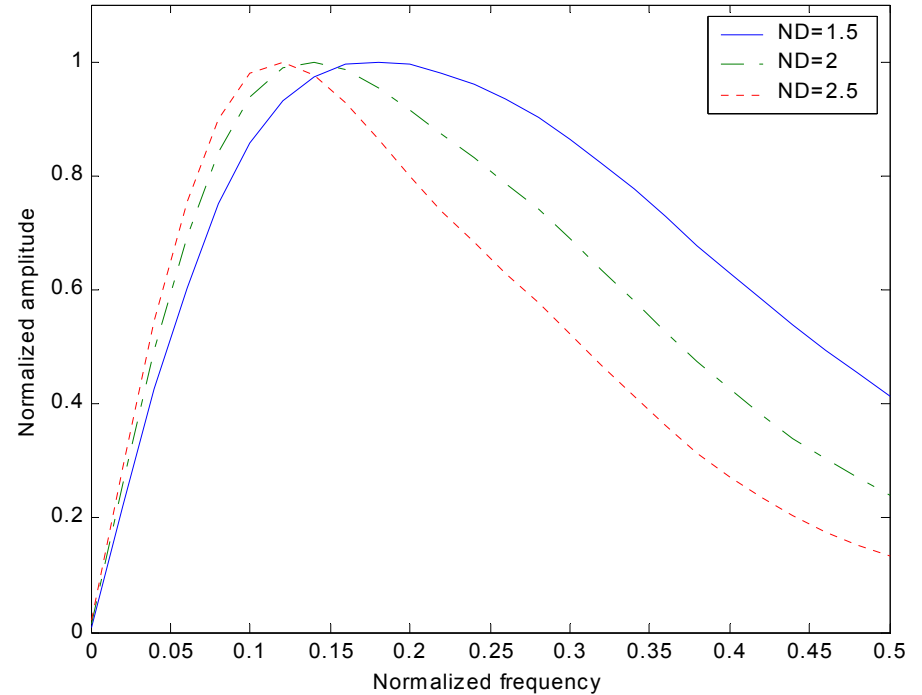
Frequency Responses of Dibit responses

Frequency responses of a Perpendicular model



Perpendicular model

Frequency responses for a Longitudinal model



Longitudinal model

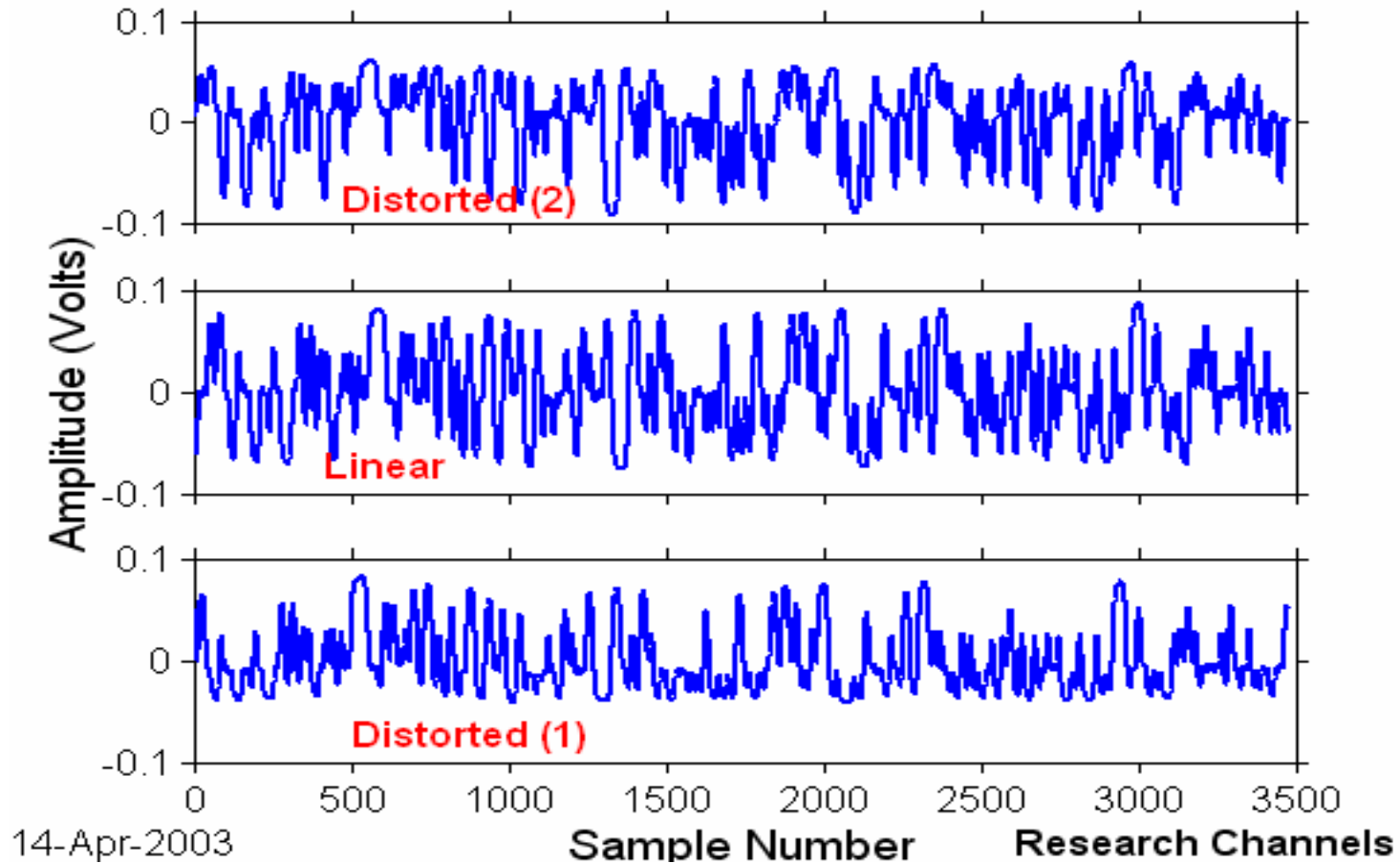
Reality is Quite Different

- Signal suffers from nonlinearities
 - NLTS
 - MR Asymmetry
 - Base Line Wanders
 - TAs
 - Other distortions

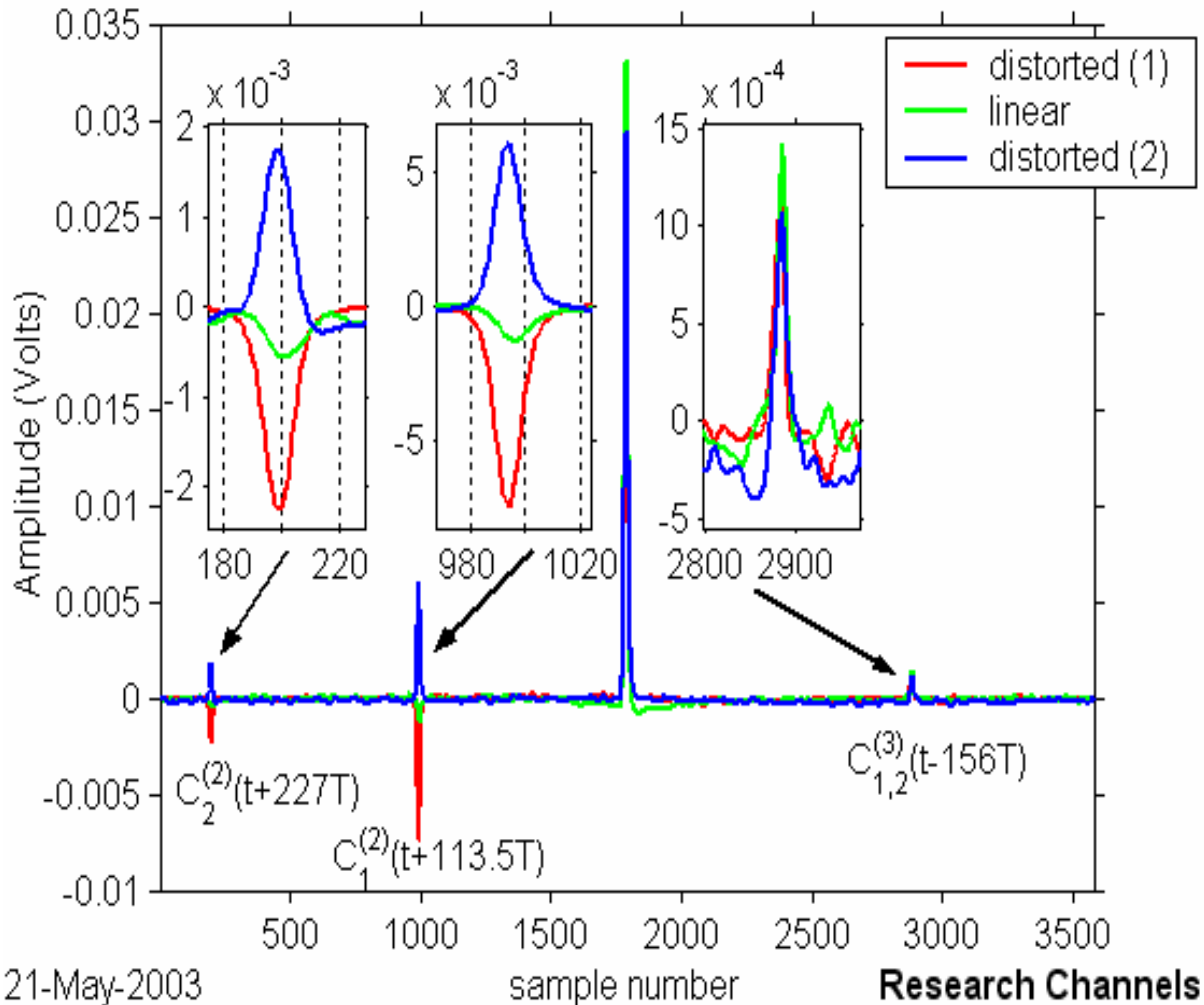
- Noise is Non-Gaussian

- Noise is Signal Dependent

Noise Free Real Signals with Nonlinearities



Extracted Dibit Response



extracted dibit

- provides information about systems linear response.
- is a convenient means for identifying nonlinearities present in system that show up as echoes around the main pulse.

Volterra Model of a Readback Signal

$$\begin{aligned}
 y(t) = & \sum_k a_k C^{(1)}(t - kT) \\
 & + \sum_k a_k a_{k-1} C_1^{(2)}(t - kT) + \sum_k a_k a_{k-2} C_2^{(2)}(t - kT) + \dots \\
 & + \sum_k a_k a_{k-1} a_{k-2} C_{1,2}^{(3)}(t - kT) + \sum_k a_k a_{k-1} a_{k-3} C_{1,3}^{(3)}(t - kT) + \dots
 \end{aligned}$$

The equation is annotated with several callouts:

- First Order Kernel**: Points to the first term $\sum_k a_k C^{(1)}(t - kT)$.
- Linear Response**: Points to the entire first-order term.
- Second Order Kernels**: Points to the second-order terms $\sum_k a_k a_{k-1} C_1^{(2)}(t - kT) + \sum_k a_k a_{k-2} C_2^{(2)}(t - kT)$.
- Second Order Non-linear Response**: Points to the second-order terms.
- Third Order Kernels**: Points to the third-order terms $\sum_k a_k a_{k-1} a_{k-2} C_{1,2}^{(3)}(t - kT) + \sum_k a_k a_{k-1} a_{k-3} C_{1,3}^{(3)}(t - kT)$.
- Third Order Non-linear Response**: Points to the third-order terms.
- Memory Length**: Points to the summation index k .

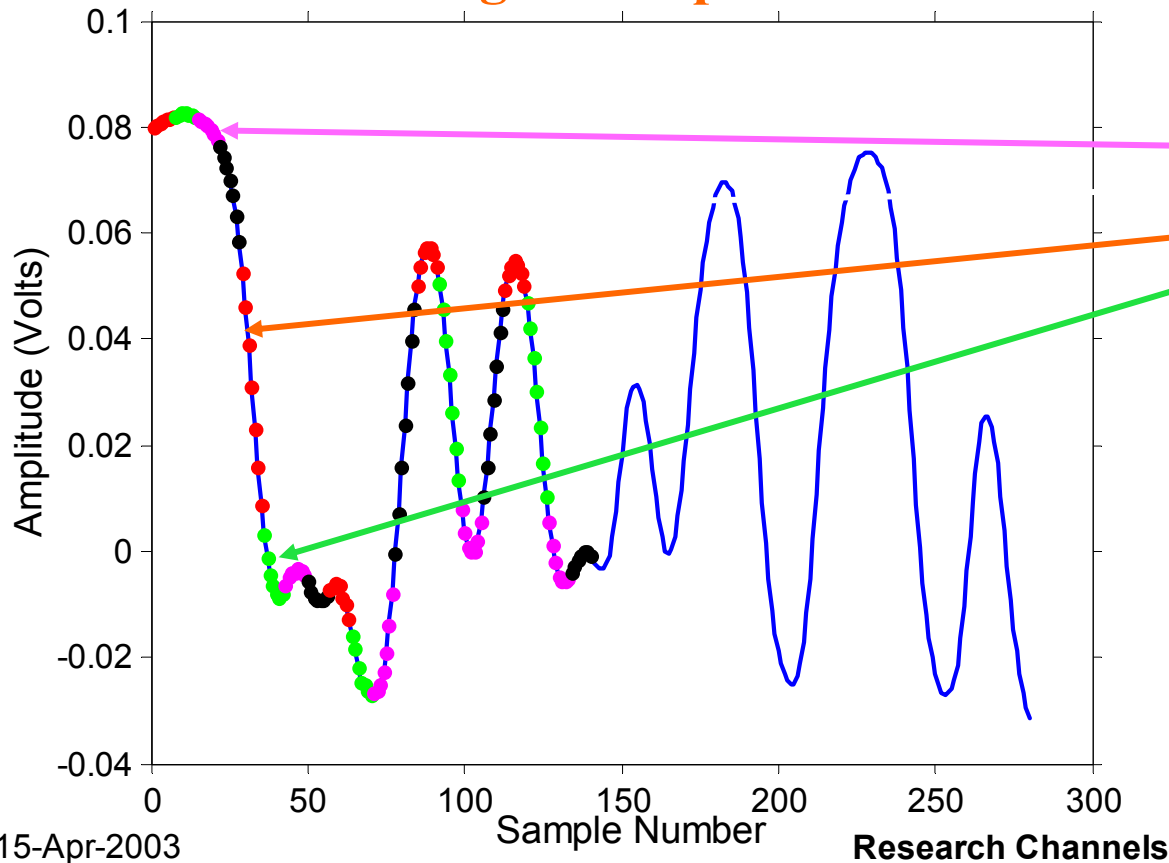
VM can be characterized by 2^{L-1} kernels, $C^{(l)}(t), l = 2, \dots, L$

For magnetic recording, only a few of the kernels are significant.

A rule of thumb: $L \sim$ the extent of the dipulse (in units of bit interval, T)

VM Kernels can be conveniently identified from measured PRBS signals

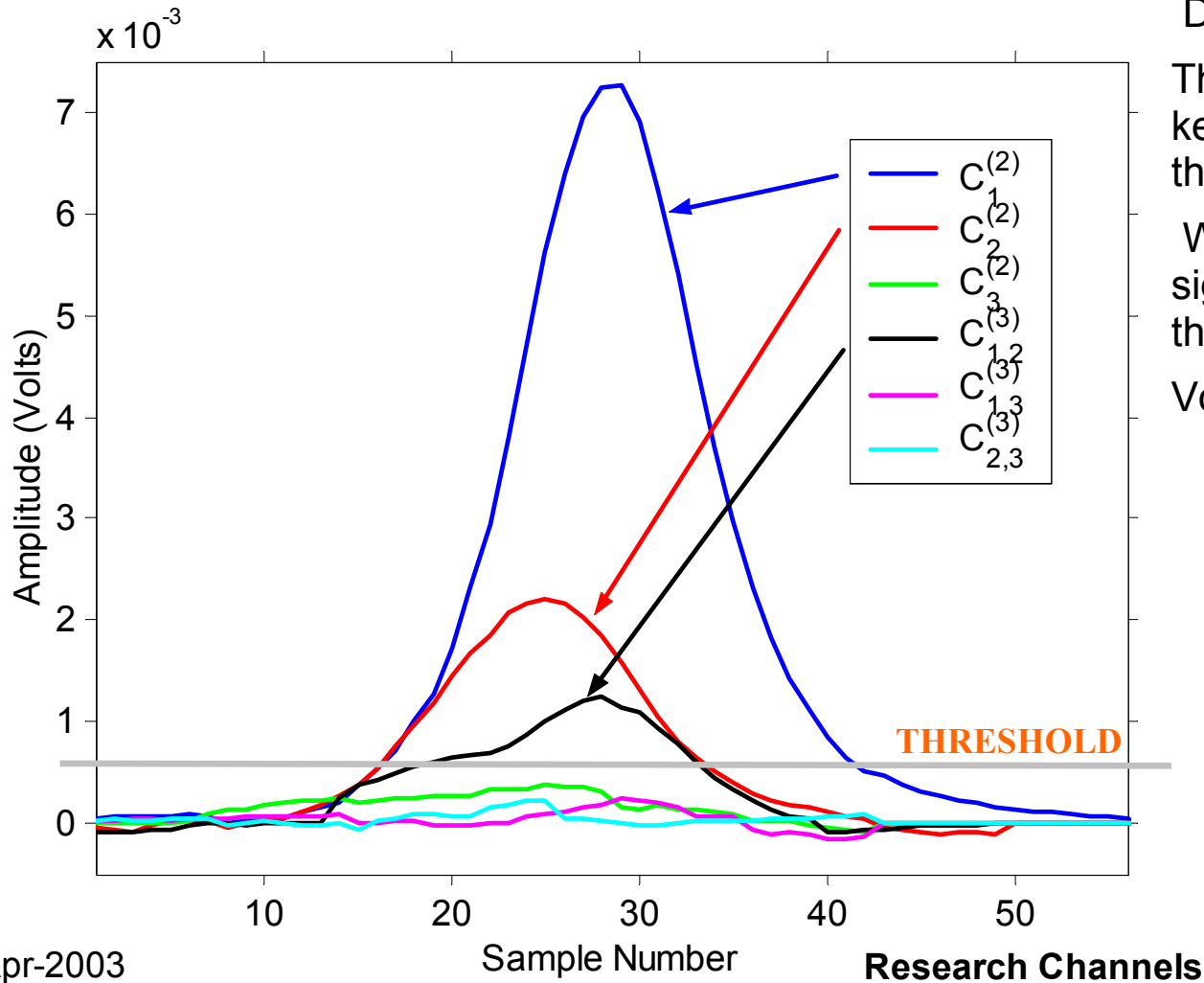
Signal Chips



All Patterns of Length L=9									
	a ₄	a ₃	a ₂	a ₁	a ₀	a ₁	a ₂	a ₃	a ₄
1	1	1	1	1	1	1	1	1	1
2	1	1	1	1	1	1	1	1	-1
3	1	1	1	1	1	1	1	-1	1
4	1	1	1	1	1	1	-1	1	-1
5	1	1	1	1	1	-1	1	-1	1
6	1	1	1	1	-1	1	-1	1	-1
7	1	1	1	-1	1	-1	1	-1	-1
•			•			•			•
•			•			•			•
•			•			•			•
506	-1	1	1	-1	1	-1	1	1	1
507	1	1	-1	1	-1	1	1	1	1
508	1	-1	1	-1	1	1	1	1	1
509	-1	1	-1	1	1	1	1	1	1
510	1	-1	1	1	1	1	1	1	1
511	-1	1	1	1	1	1	1	1	1
512	-1	-1	-1	-1	-1	-1	-1	-1	-1

No signal chip

Identification of Kernels



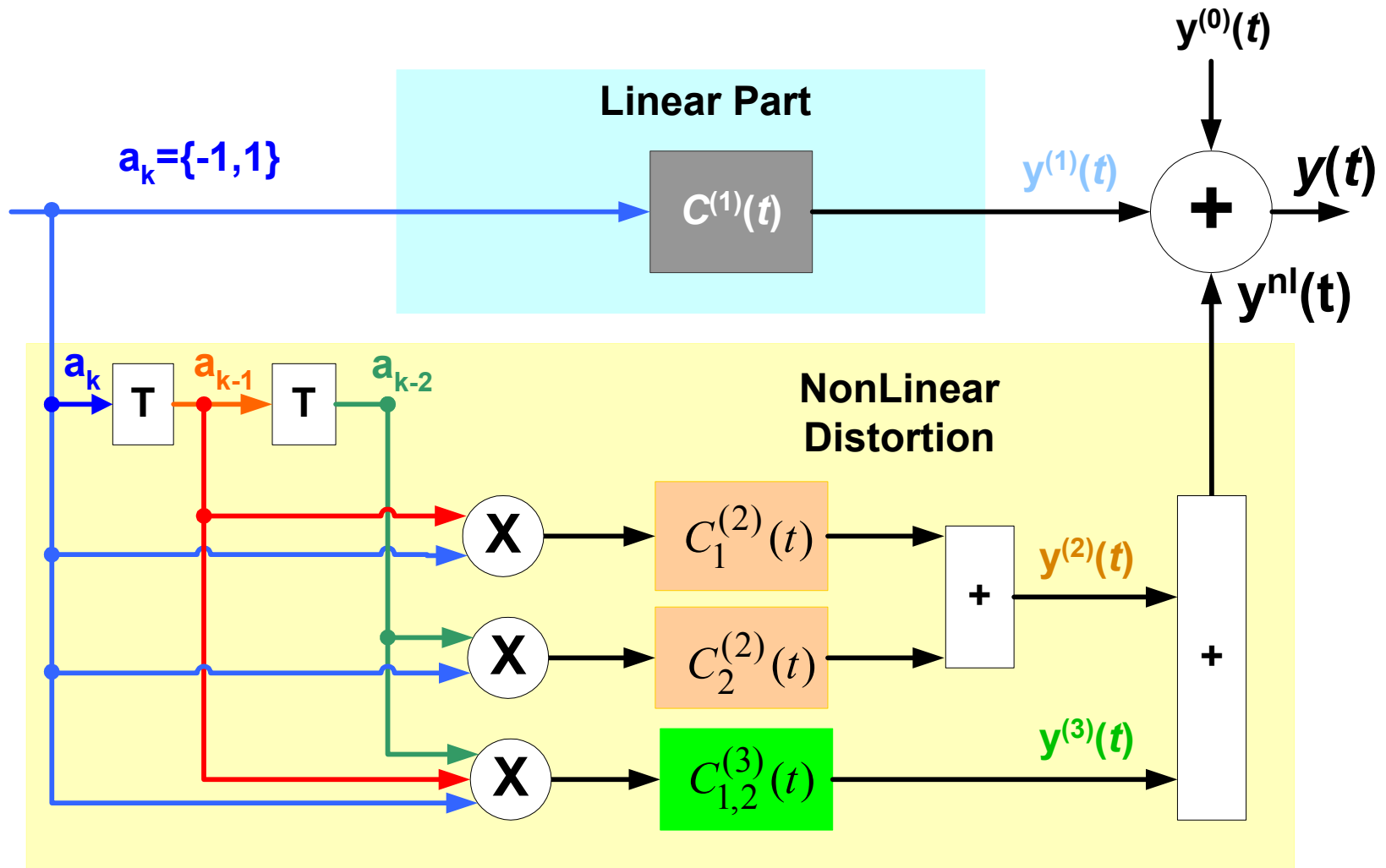
Distorted (1)

There are only three kernels above the threshold

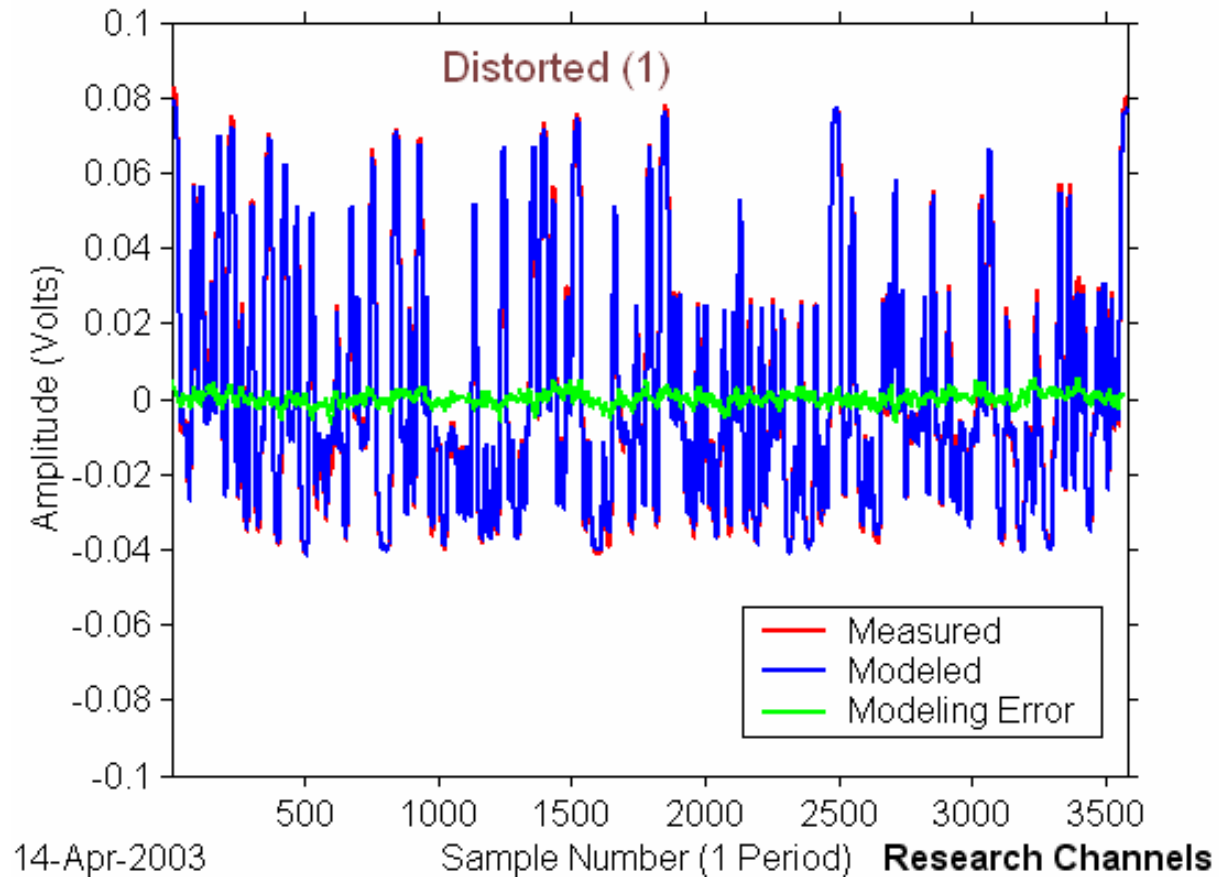
We declare them as significant and include in the Reduced Complexity Volterra Model.

15-Apr-2003

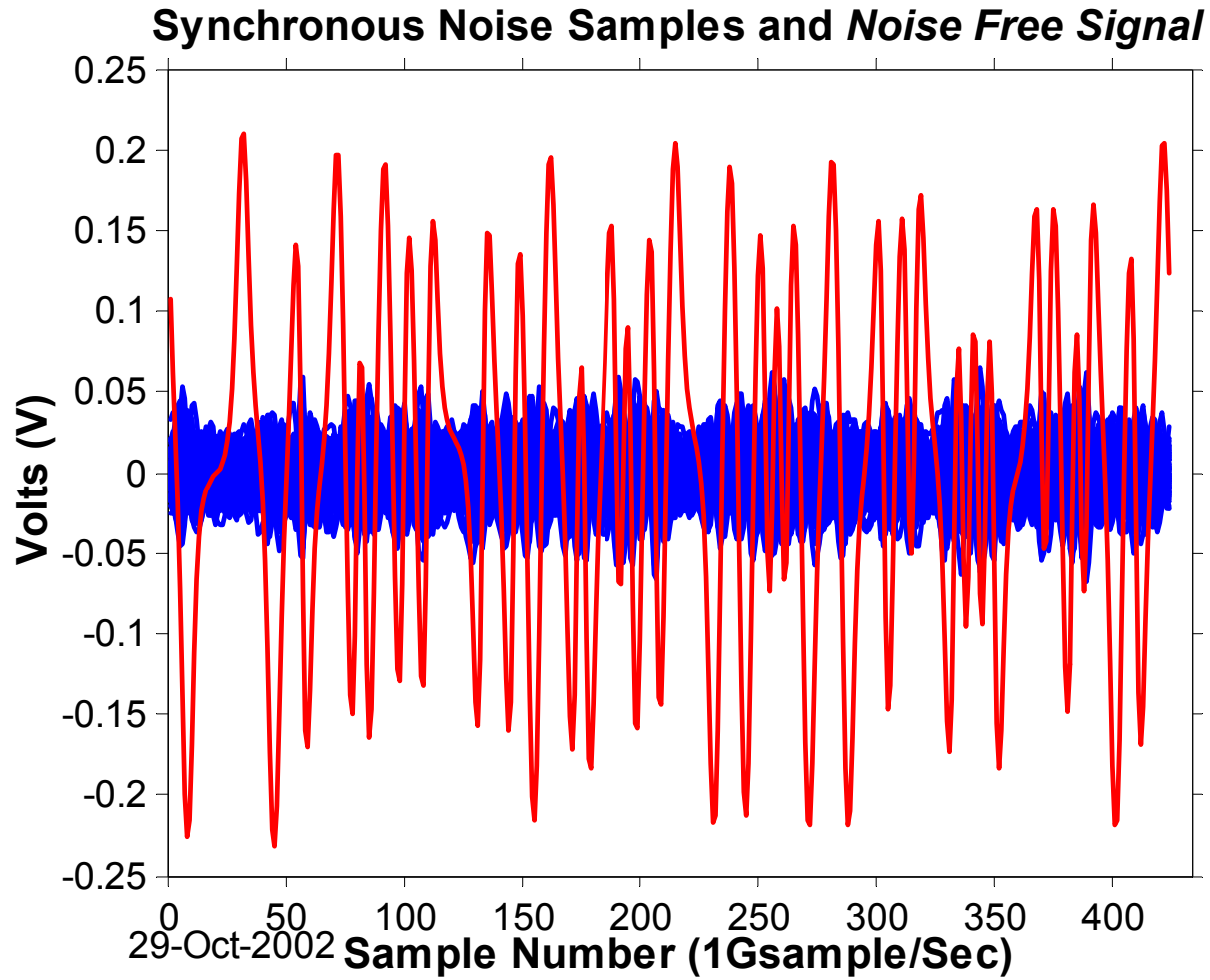
Volterra Model Block Diagram



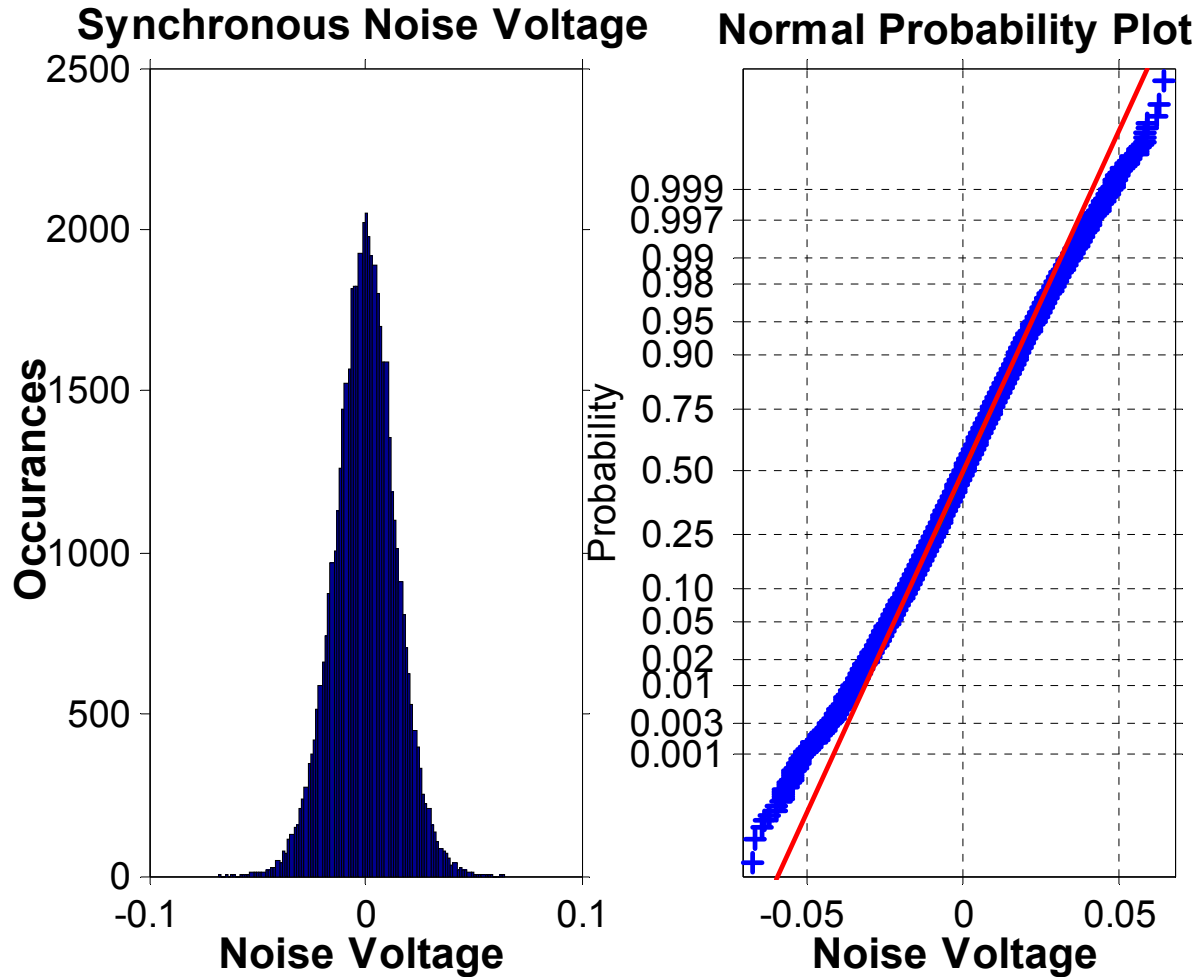
How Good is VM?



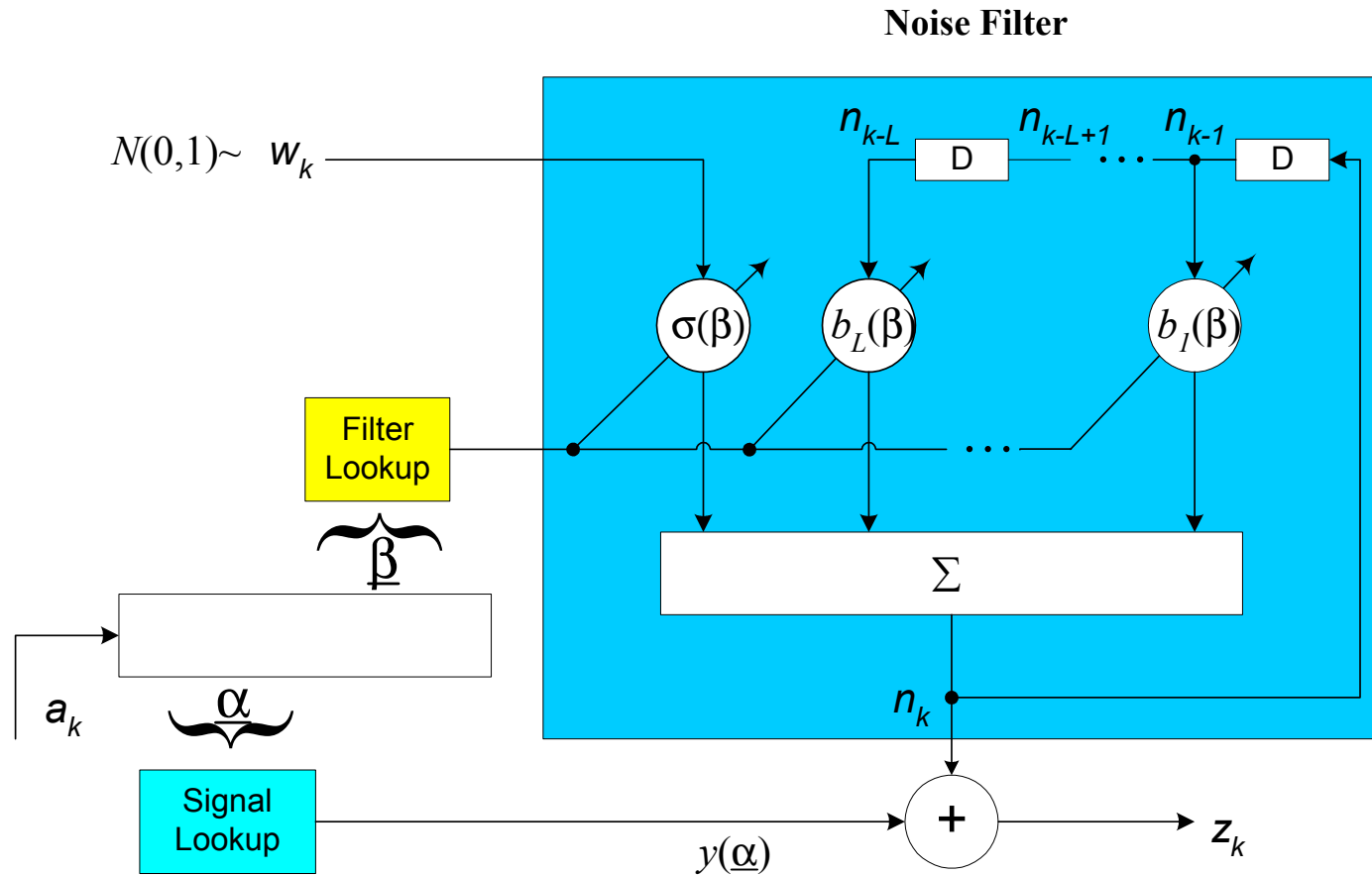
Longitudinal Media Noise and Signal



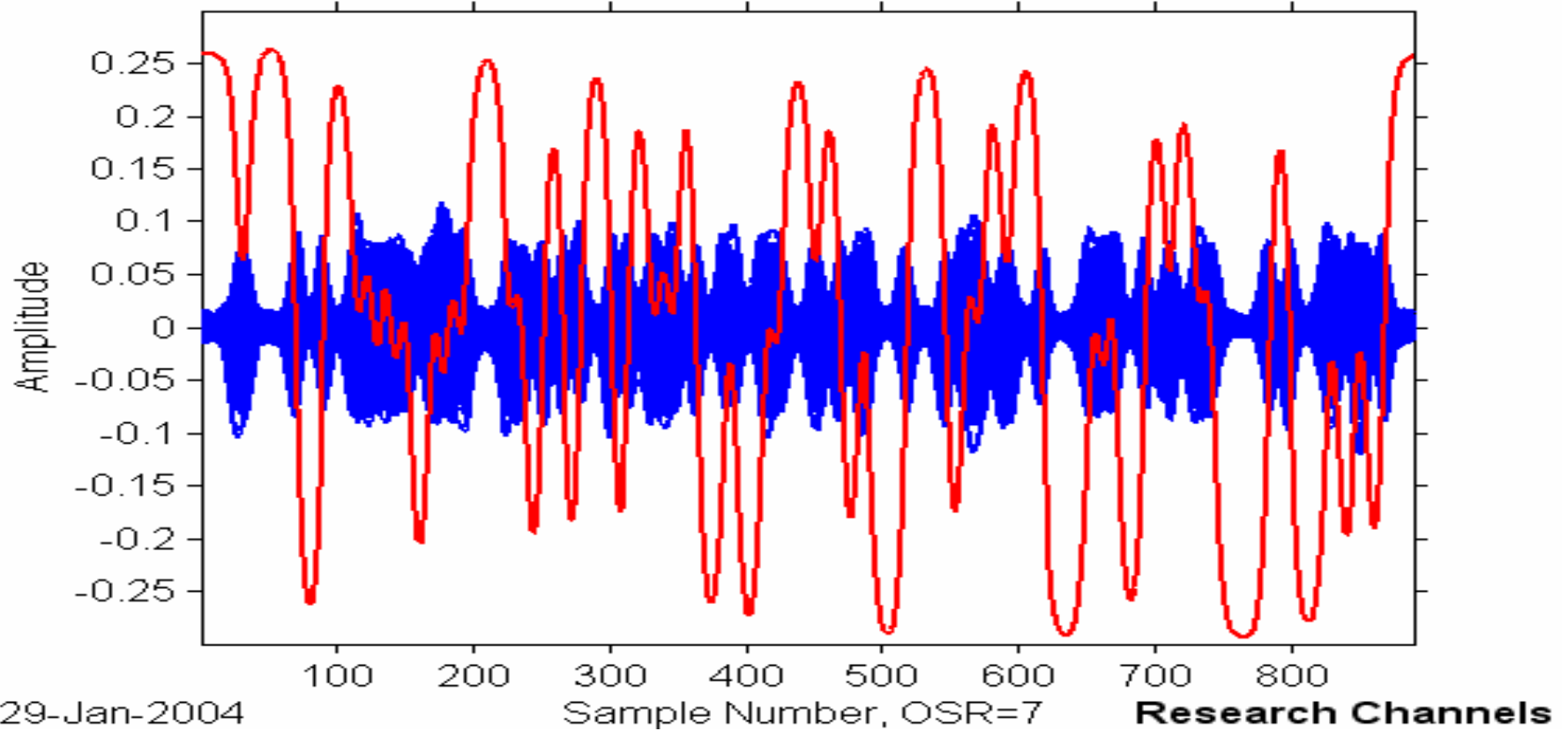
Longitudinal: Media Noise Voltage



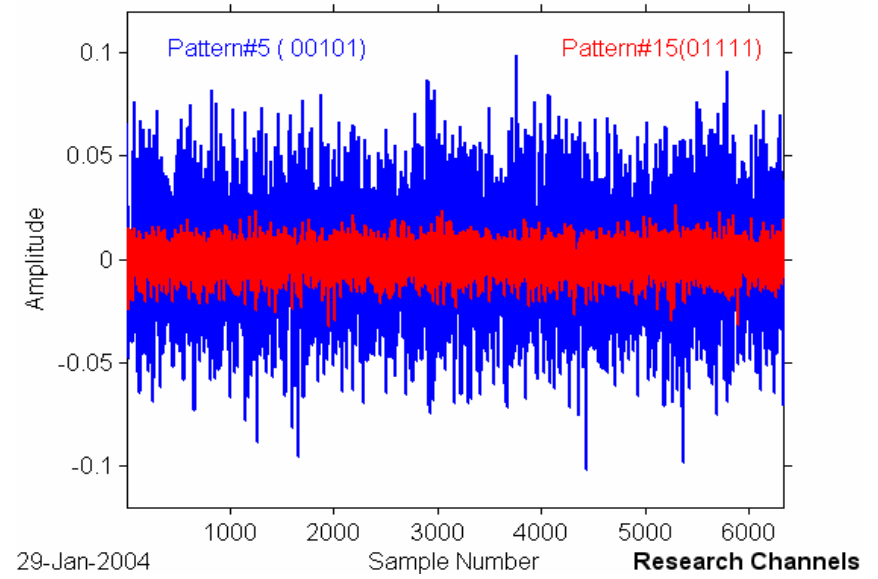
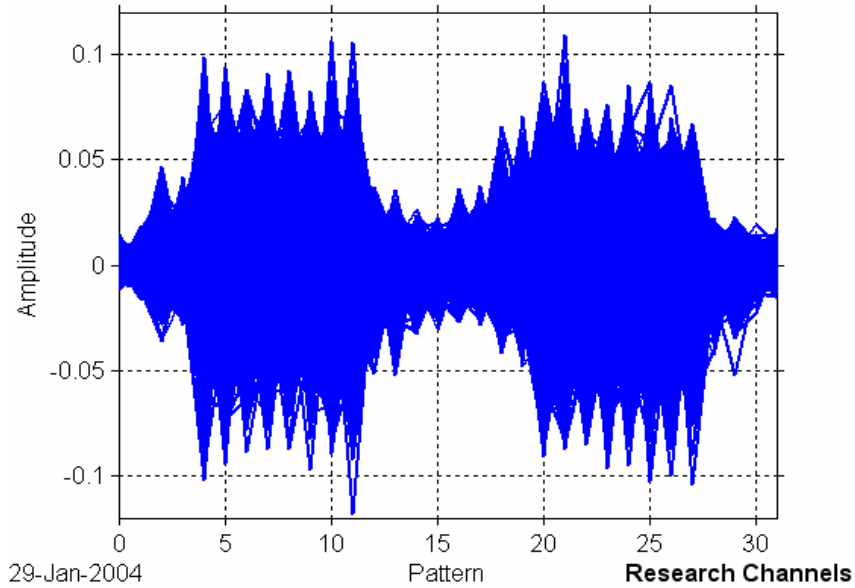
Data Dependent AR Model (AR)



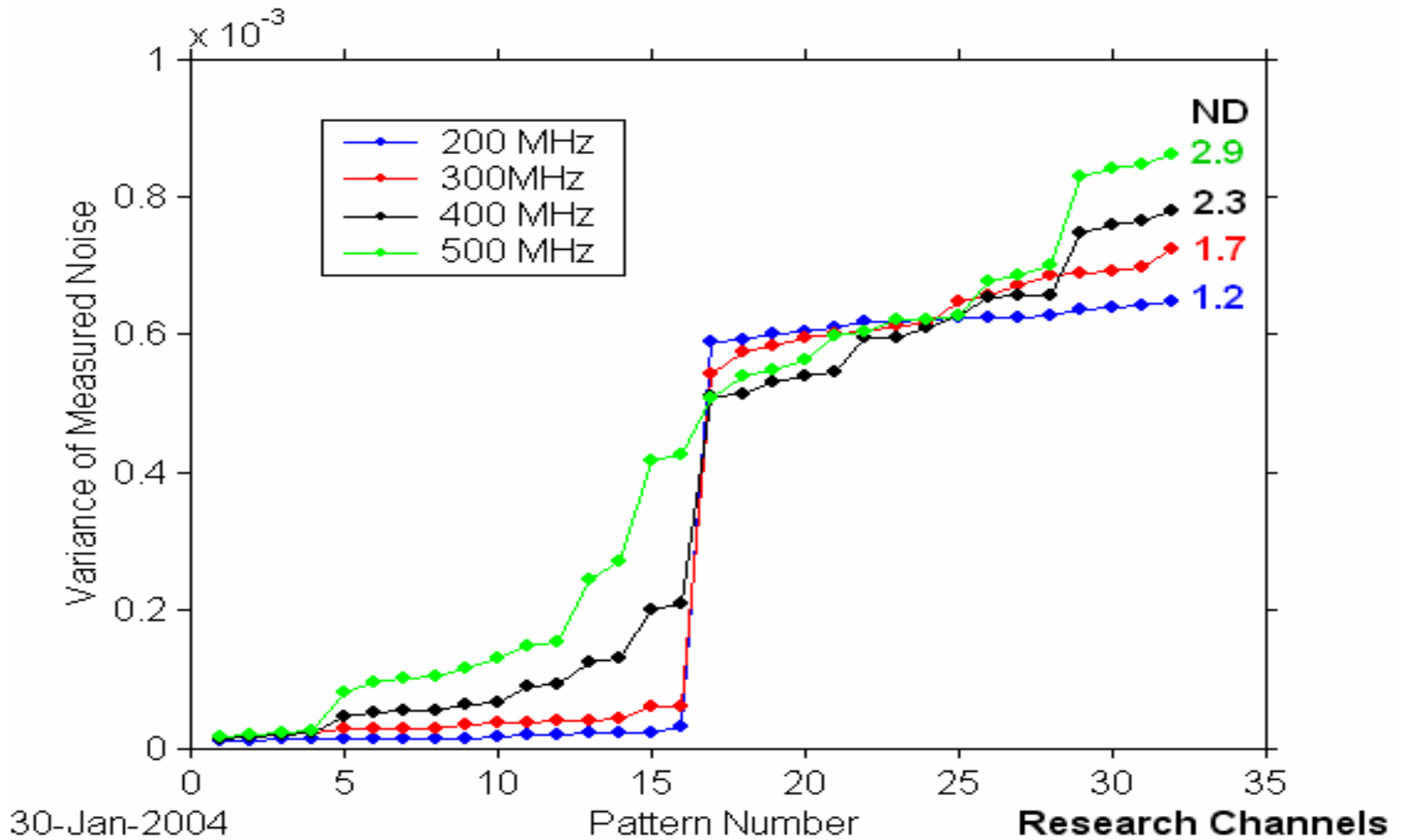
Perpendicular Signal and Media Noise



Media Noise 400 MHz

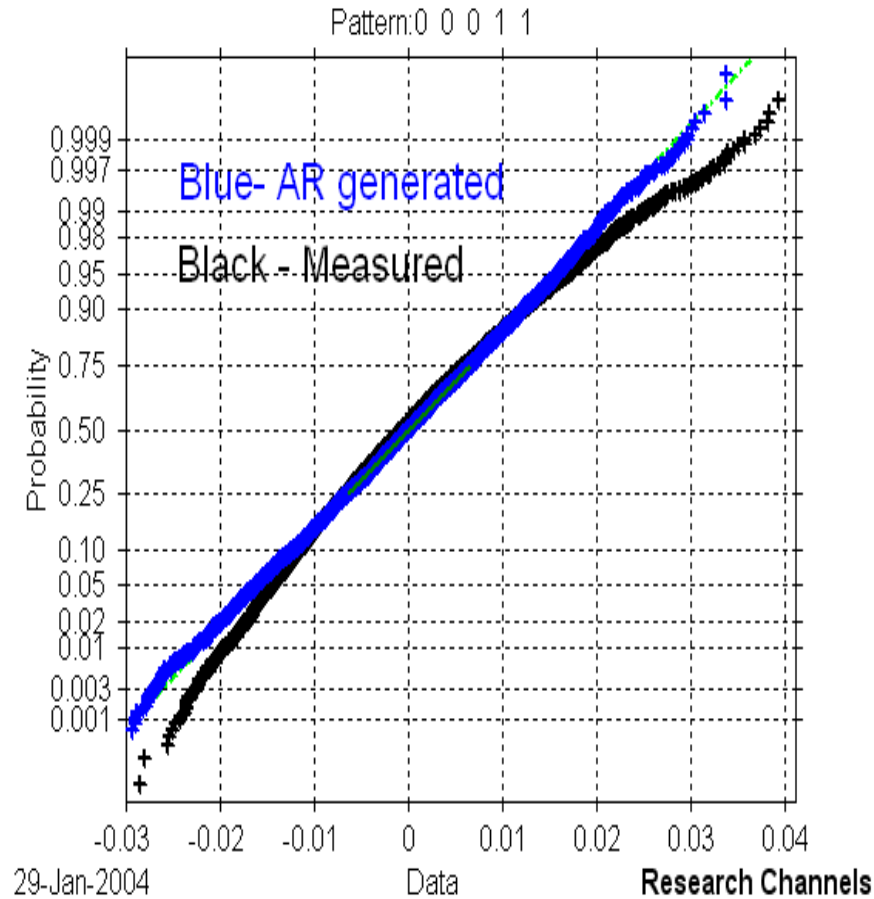


As ND Increases Noise Variance vs. Pattern

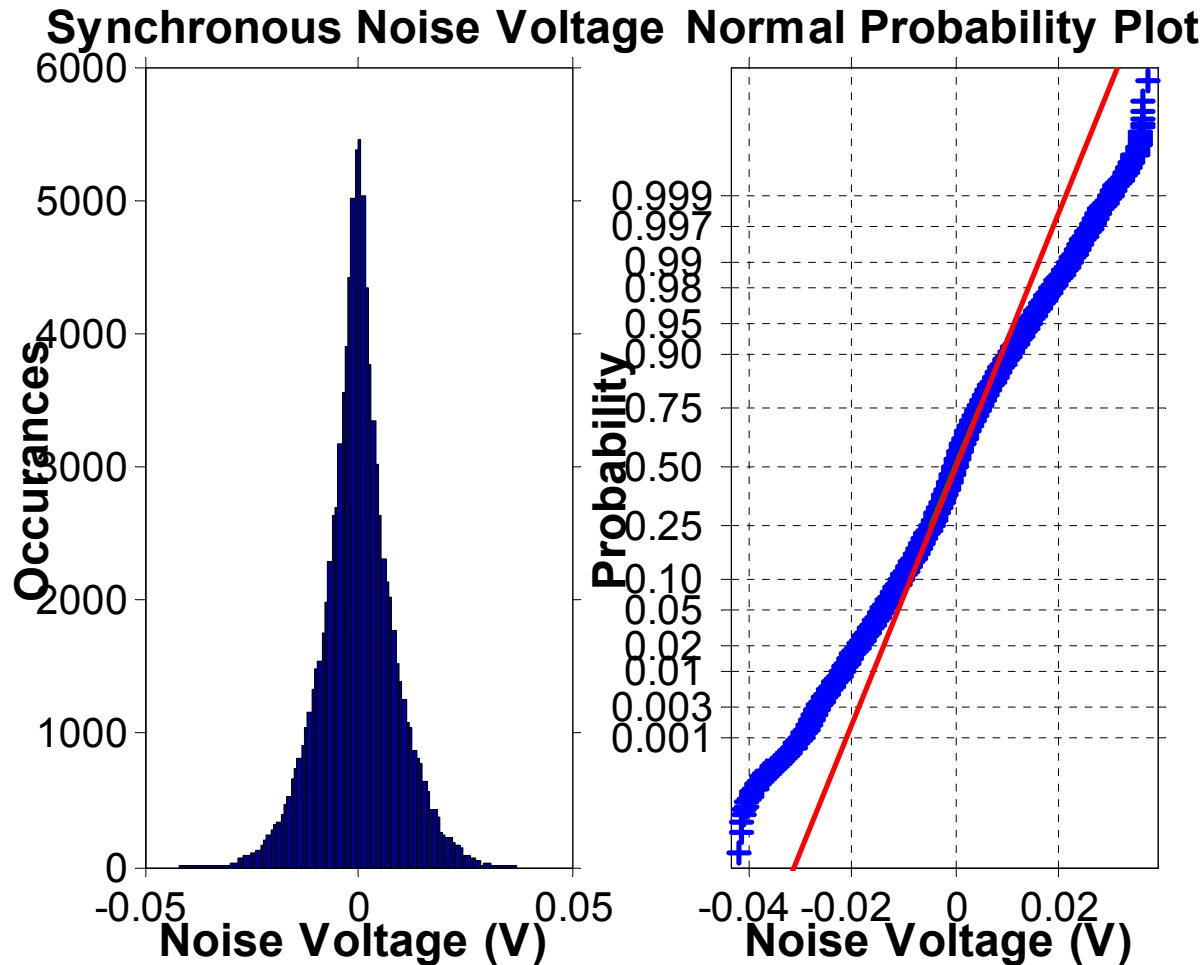


AR noise generation

- not a great fit

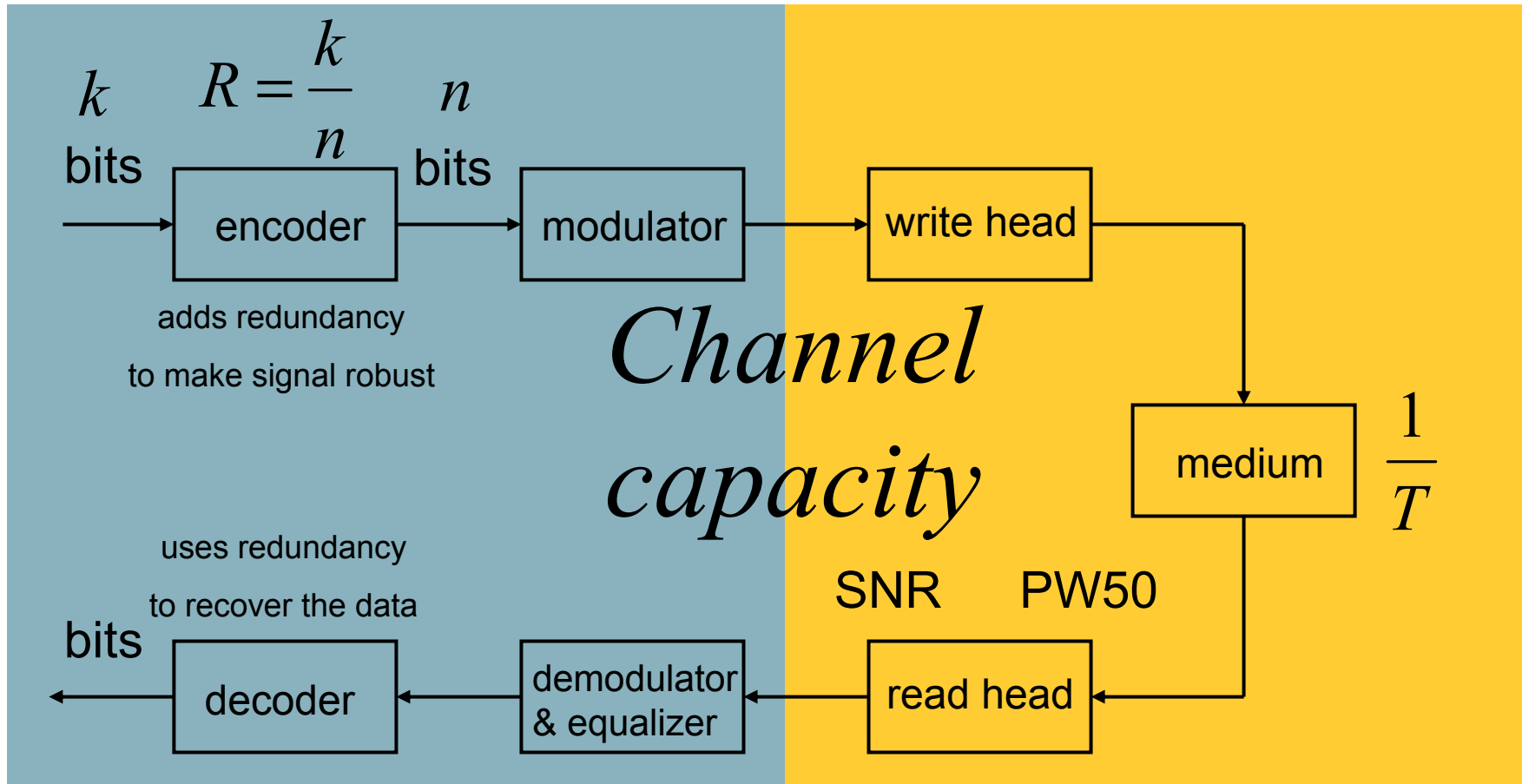


Perpendicular: Media Noise Voltage

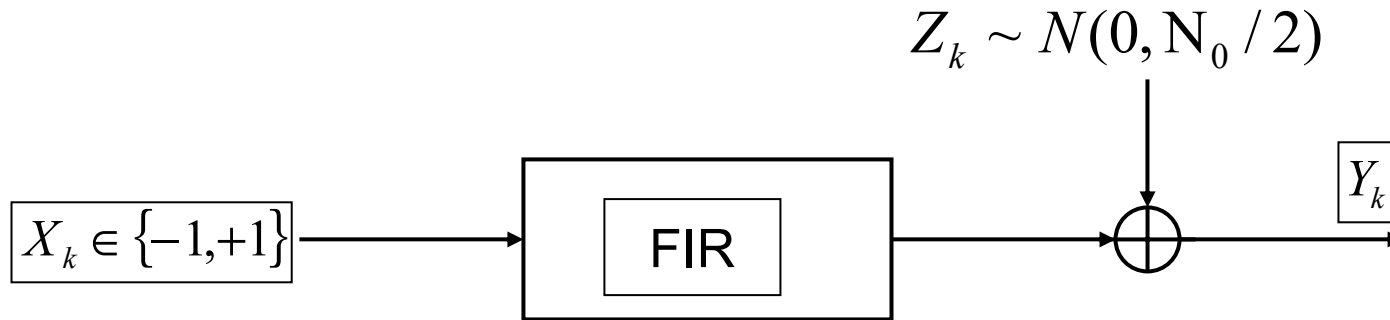


- Noise distribution does not fit Gaussian!
- Noise distribution looks more like a laplacian.

Generic Storage Channel



Brief Survey of the Literature



Bounds

Shamai et al. 1991, McLaughlin and Neuhoff 1993, and many others

– Direct Computation

Hirt 1988

– Markov-Chain Monte-Carlo Method

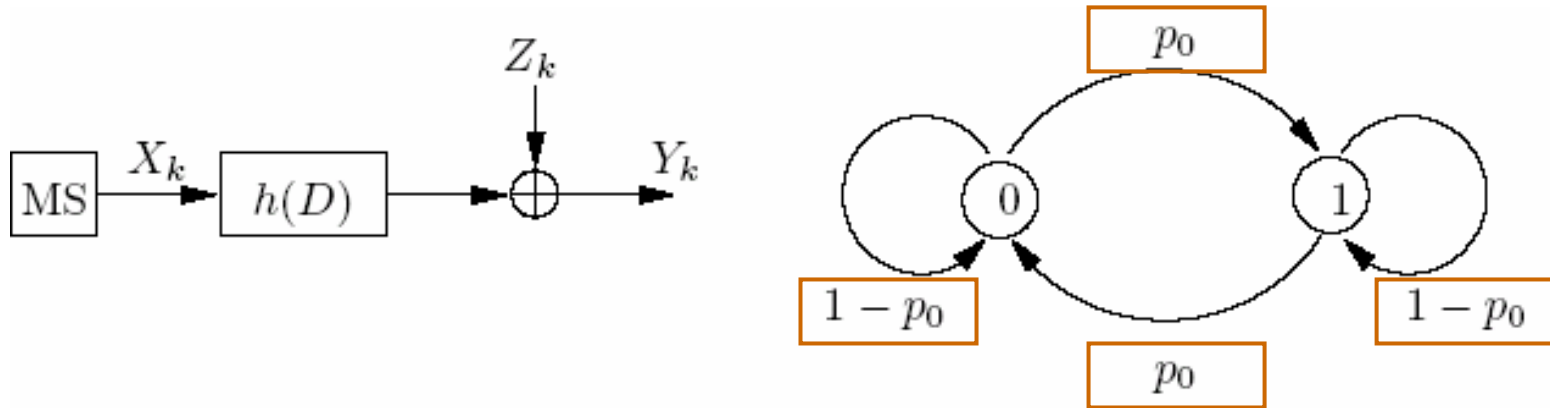
Arnold and Loeliger, Pfister et al., Sharma and Singh, Vontobel, all in 2001

– Shamai-Laroia conjecture

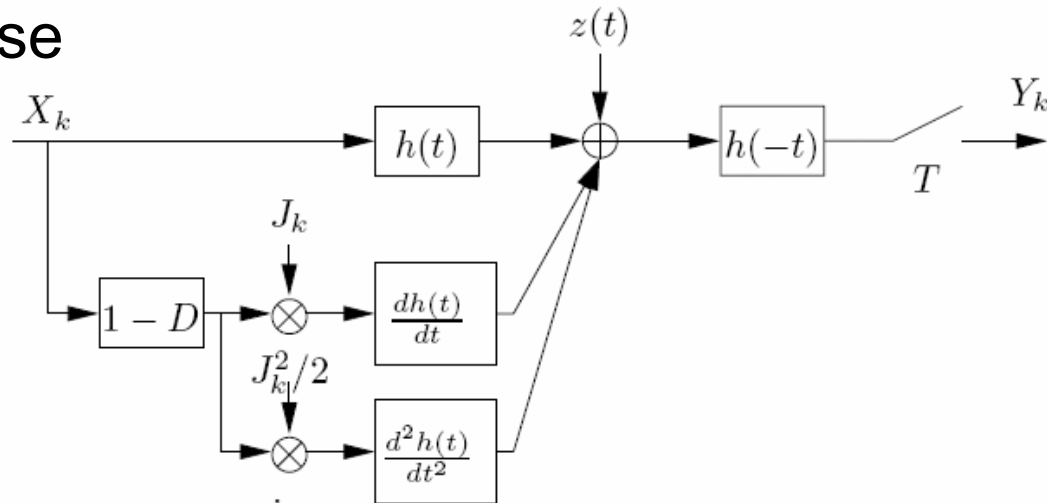
Shamai-Laroia 1996, Dholakia et al. 2000, Arnold and Eleftheriou 2002

Brief Survey of the Literature (cont.)

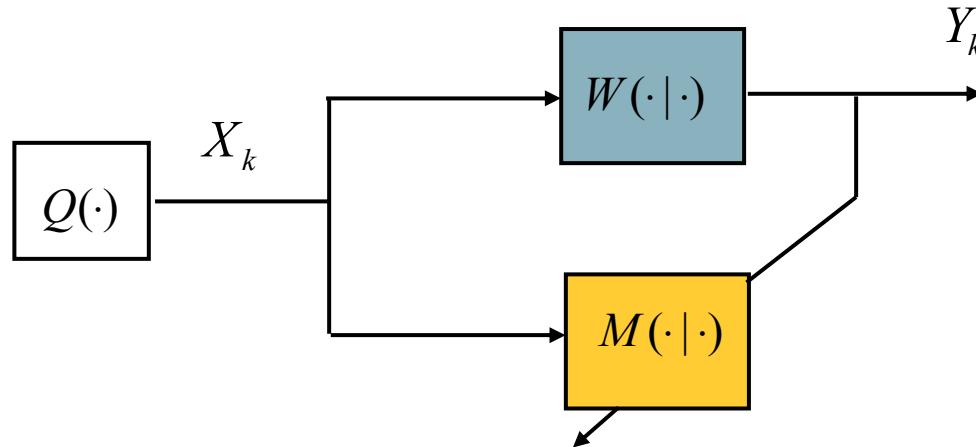
Kavcic 2001:



Zhang, Duman, and Kurtas 2002: Modeling signal-dependent noise



Set-up for Mismatch Lower Bounds



Mismatch lower bound:

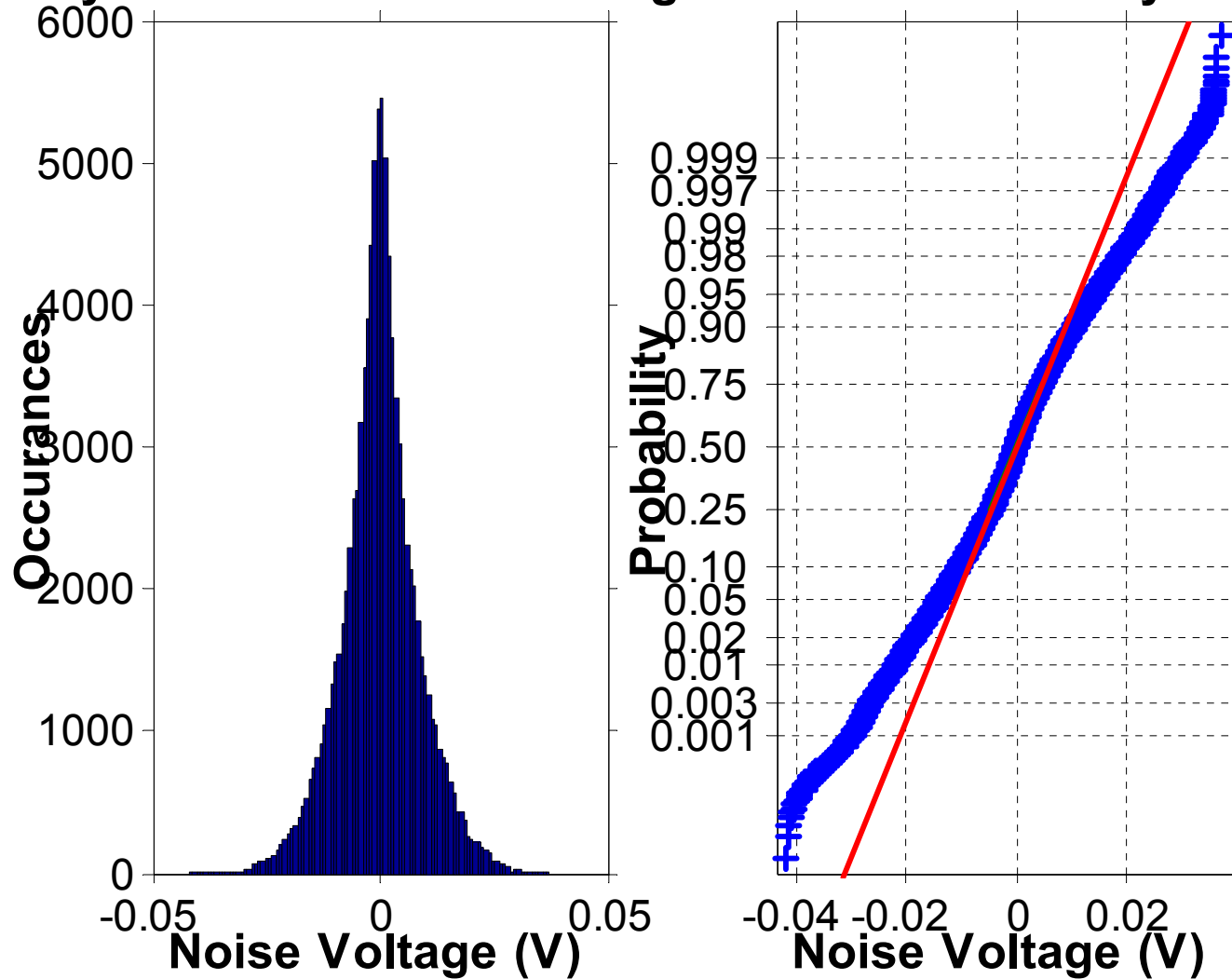
$$I(Q, M) \equiv E_{QW} [\log(QM)(Y)] - E_{QW} [\log M(Y | X)]$$

$$I(Q, W) \geq I(Q, M)$$

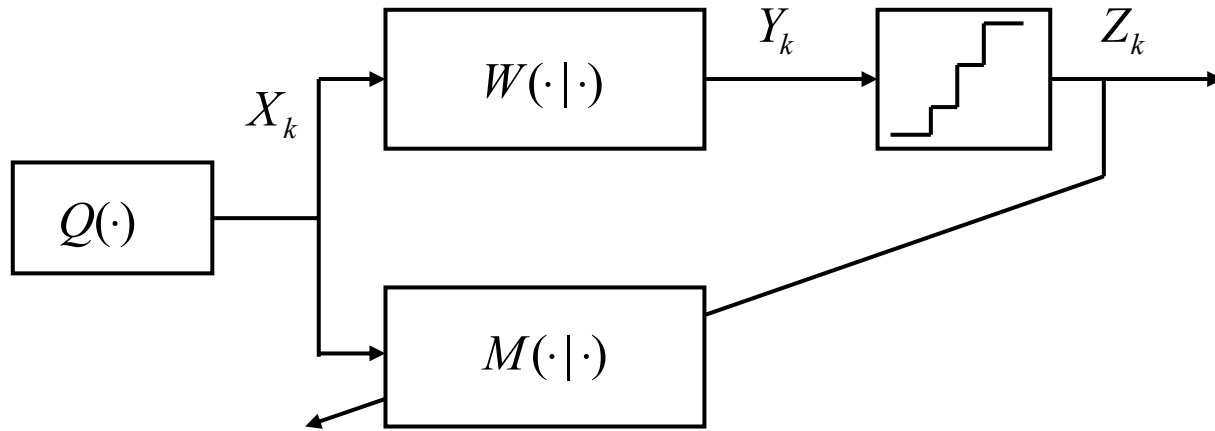
A. Ganti, A. Lapidoth, and I. E. Telatar, "Mismatched Decoding Revisited: General Alphabets, Channels with Memory, and the Wide-Band Limit," IEEE Trans. on Inform. Theory, pp. 2315-2328, Nov. 2000.

How to model the noise?

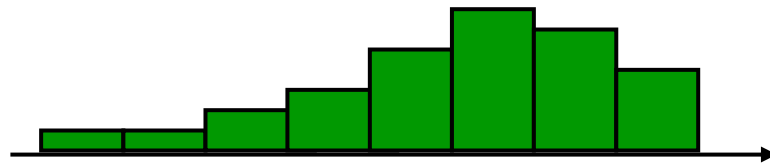
Synchronous Noise Voltage Normal Probability Plot



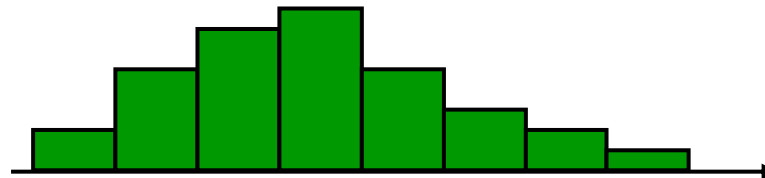
Just use histograms



(0,0)



(0,1)



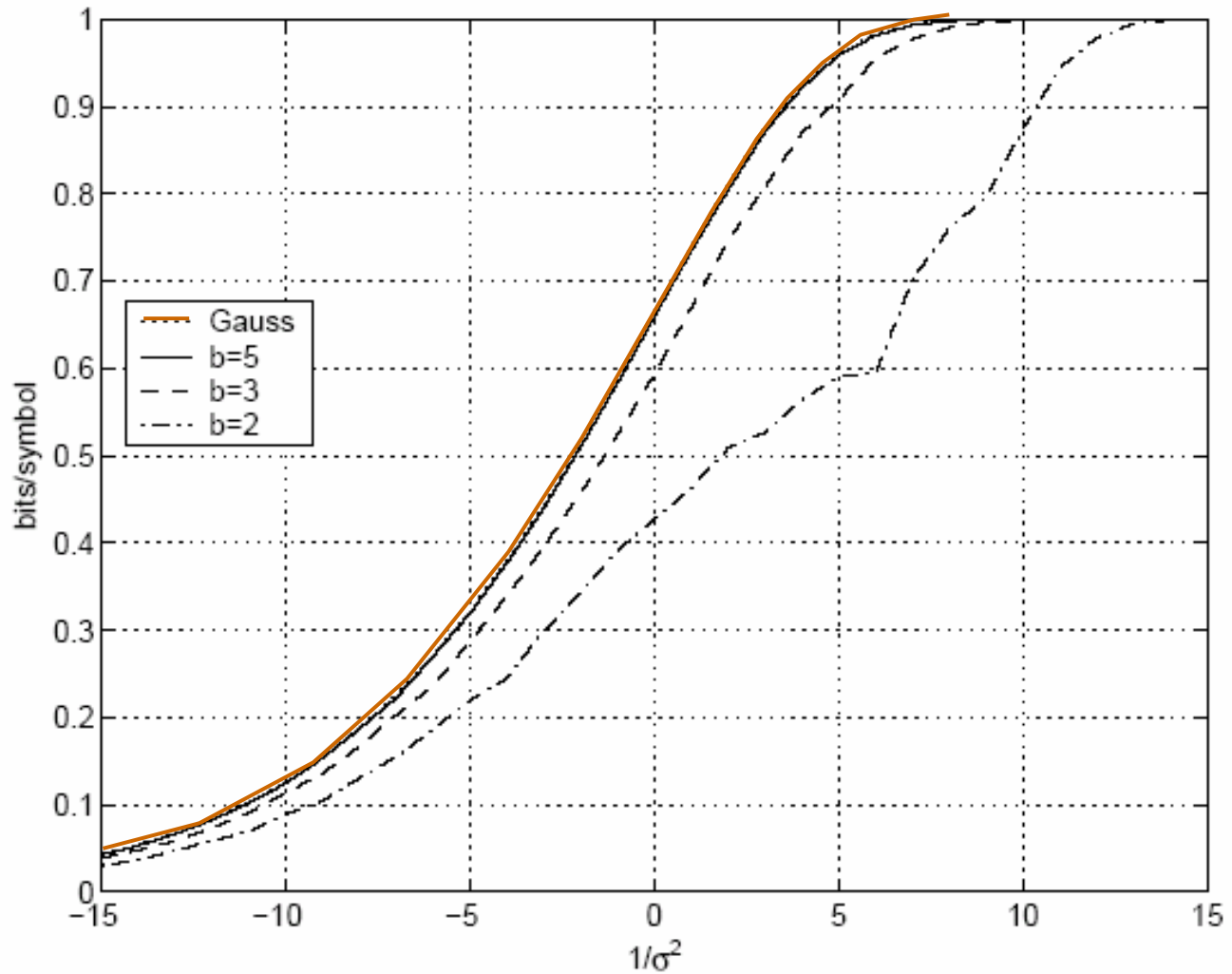
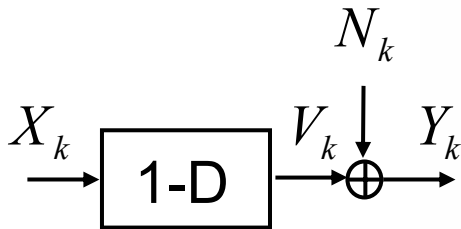
Validation on the ideal (1-D)-Channel

(1-D) channel

AWGN

$L=1$

$b=1,3,5$

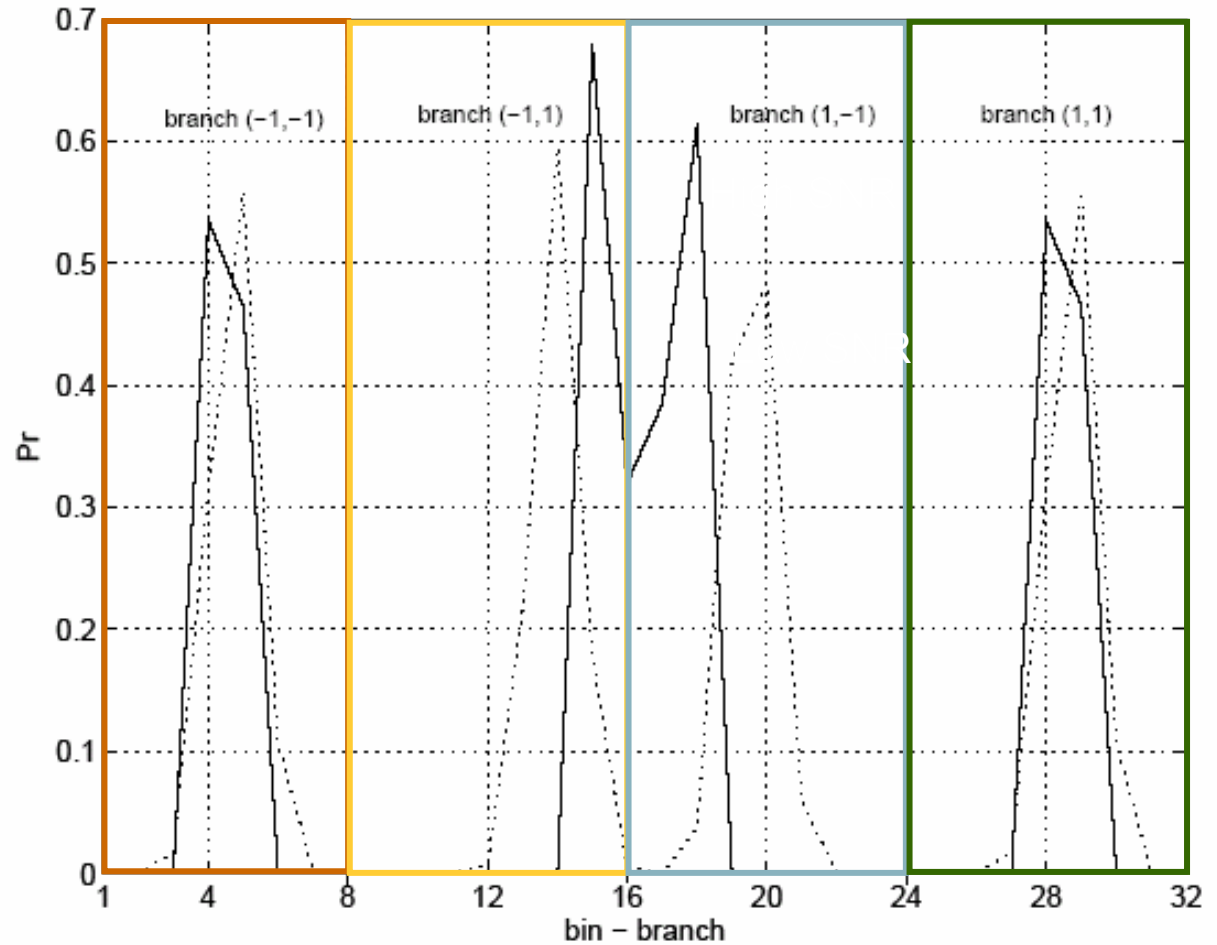
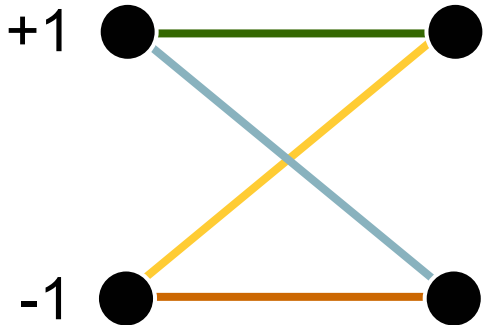


(1-D)-Channel – Histograms

(dotted for low SNR, solid for high)

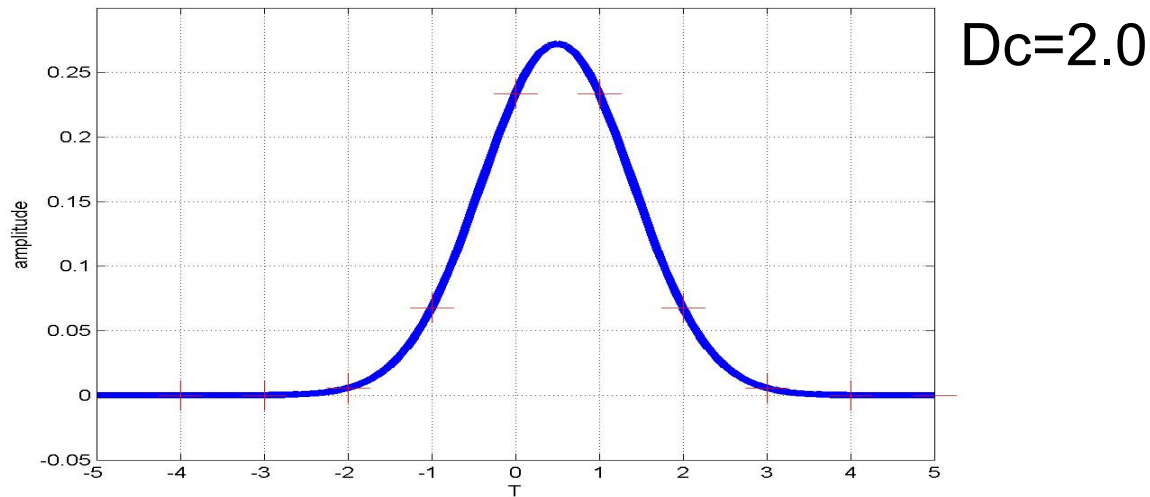
$L=1$

$b=3$



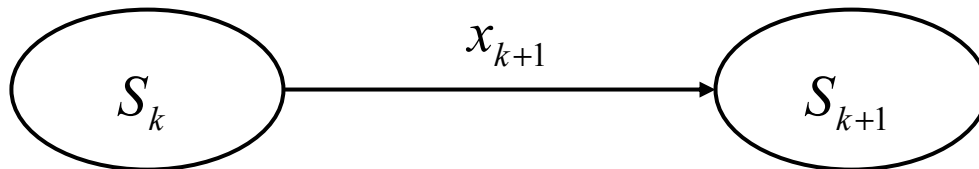
Model the channel as a GPR or FSM

1. Capturing the influence of the neighbor bits by means of a state



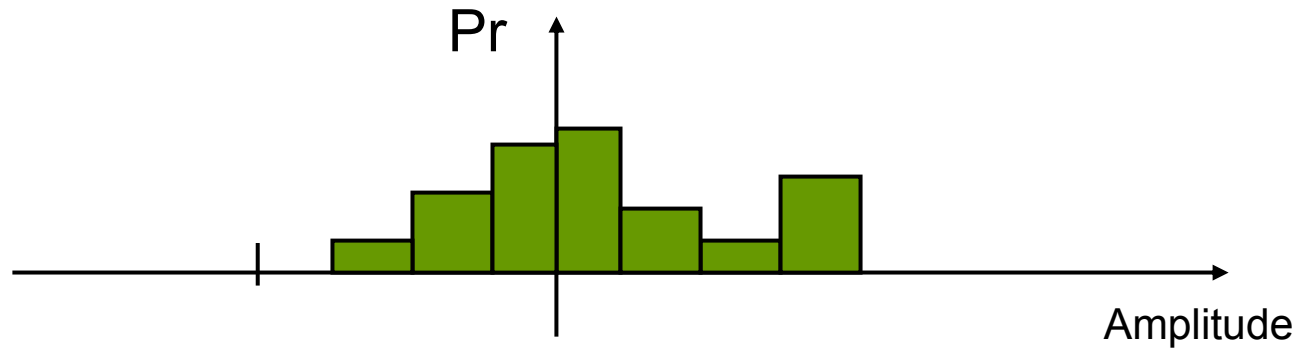
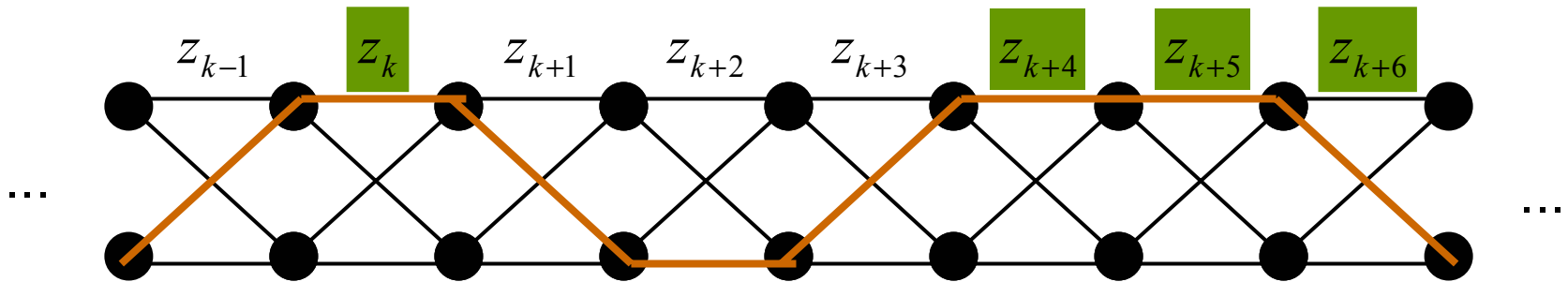
$$S_k \equiv (x_{k-m}, x_{k-(m-1)}, \dots, x_k, x_{k+1}, \dots, x_{k+m})$$

2. Sorting over time by means of a trellis of size $|S| = 2^{2m+1} = 2^L$



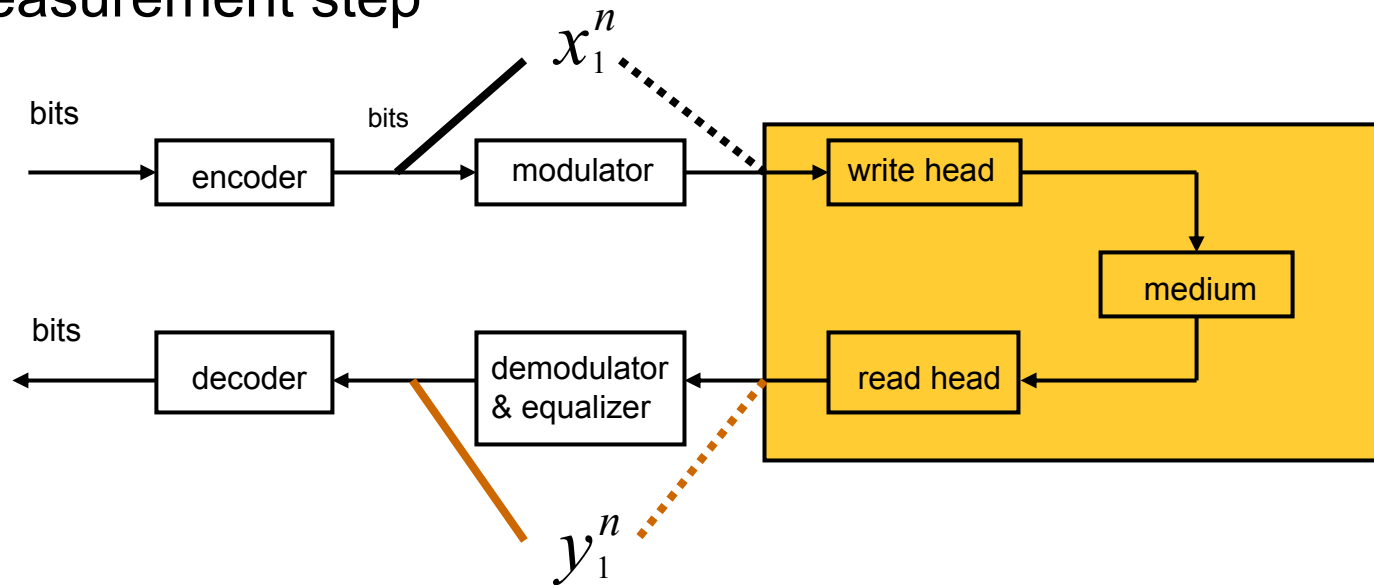
Use Quantized Histograms per Branch for Noise

3. Representation of the noise pdfs per branch:



Big Picture

1. Measurement step



2. Quantization step

$$y_1^n \stackrel{Q(b)}{\mapsto} z_1^n$$

3. Computation step

$$C \geq I_{\text{LB}} \leftarrow \frac{1}{n} \log \frac{M(Z_1^n | X_1^n)}{(QM)(Z_1^n)}$$

How complex is it?

Memory

$2 \cdot n$

of comparisons per trellis section

b

of multiplications per branch

2

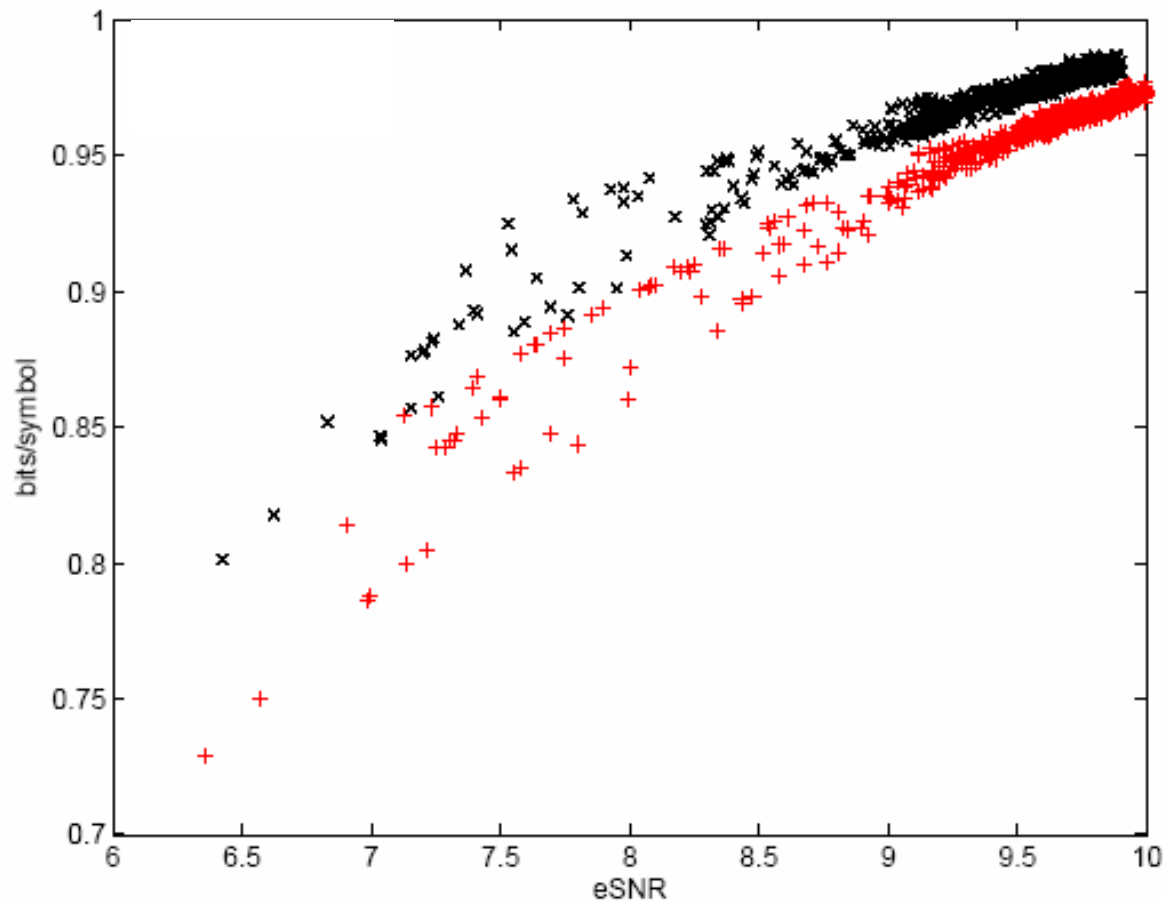
Example: $n = 10^6, |S| = 32, b = 6$

< 20 s

On a P4, 2.5 GHz, 512 MB

Orders of magnitude faster than performance evaluation of Turbo-Codes.

Results with Real Waveforms

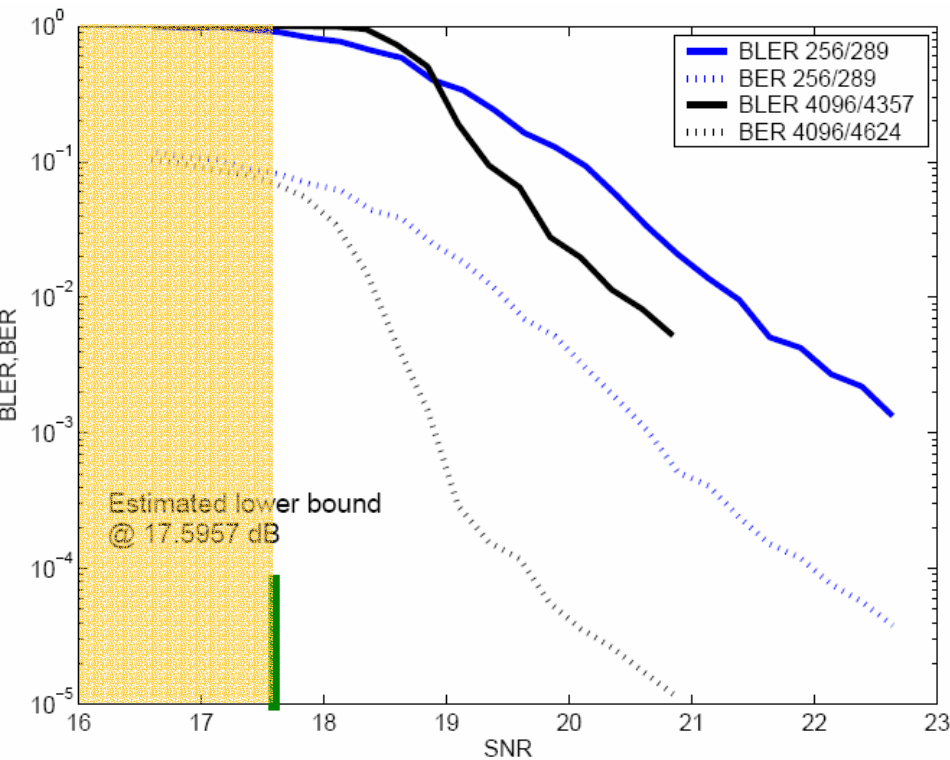


Waveform: perpendicular n=44276

Model: L=4, b=6

Compare with Turbo Codes

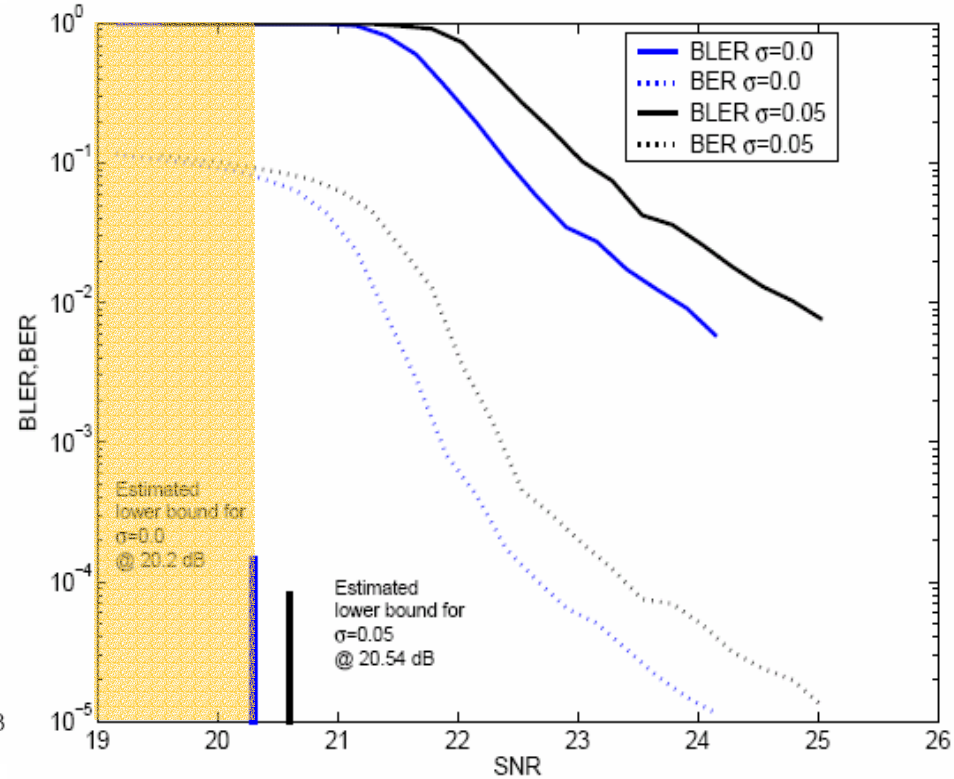
Dc=2.0



[k=256,n=289]

[k=4096,n=4624]

Dc=2.4



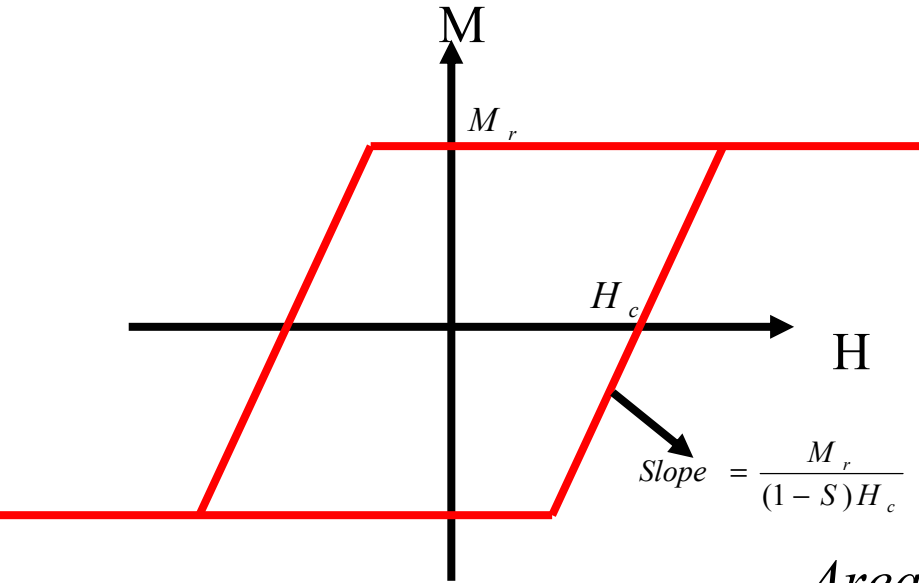
$\sigma = 0.0$

$\sigma = 0.05$

A decorative graphic on the left side of the slide, featuring a dark background with blurred, glowing blue and white binary code (0s and 1s) arranged in a grid-like pattern.

Heat Assisted Magnetic Recording

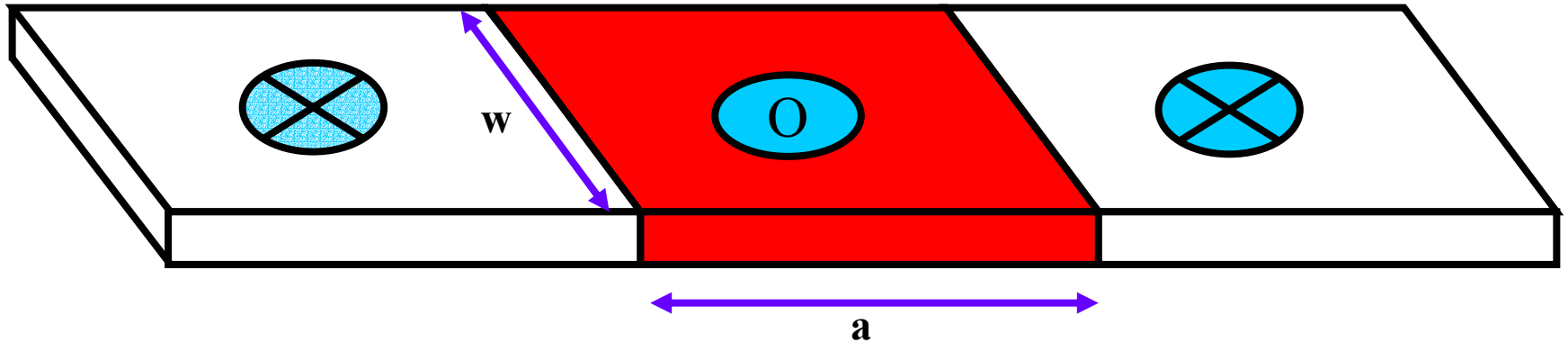
Conventional system



Store bit by

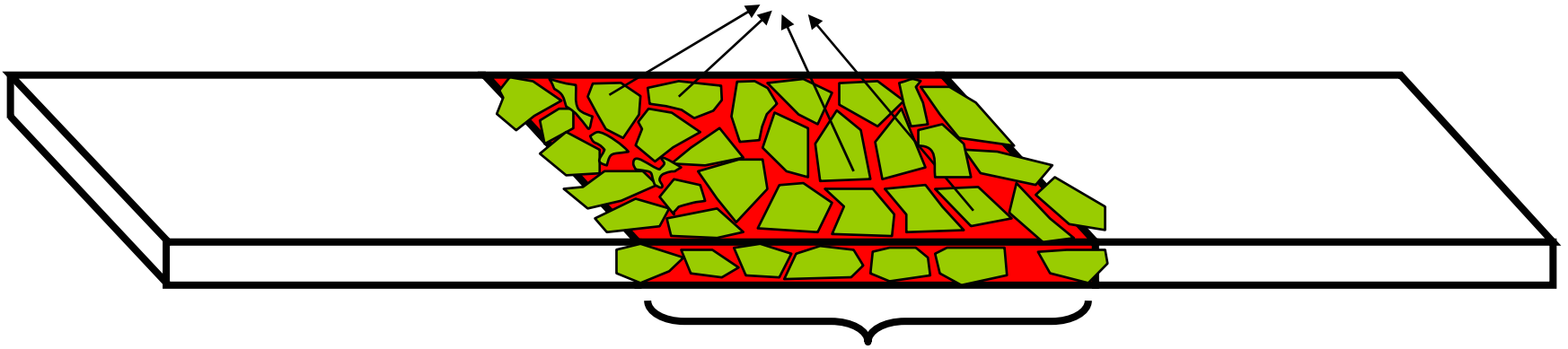
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In reality there are tiny grains

Tiny grains with finite volume V and anisotropy coefficient K_u



Minimum grain number fixed to preserve SNR

Maximum value limited by maximum writer field

Maximum Attainable
Areal Density is Limited

A solution : HAMR

Super paramagnetic limit :

$$\frac{K_u V}{k_B T} \geq M$$

Boltzmann Constant k_B

Temperature T

Large number, like 60 M

Heat Assisted Magnetic Recording

CENTRAL CONCEPT: Use interplay of temperature and field gradients to perform high density thermomagnetic recording on very high coercivity (thermally stable) media.

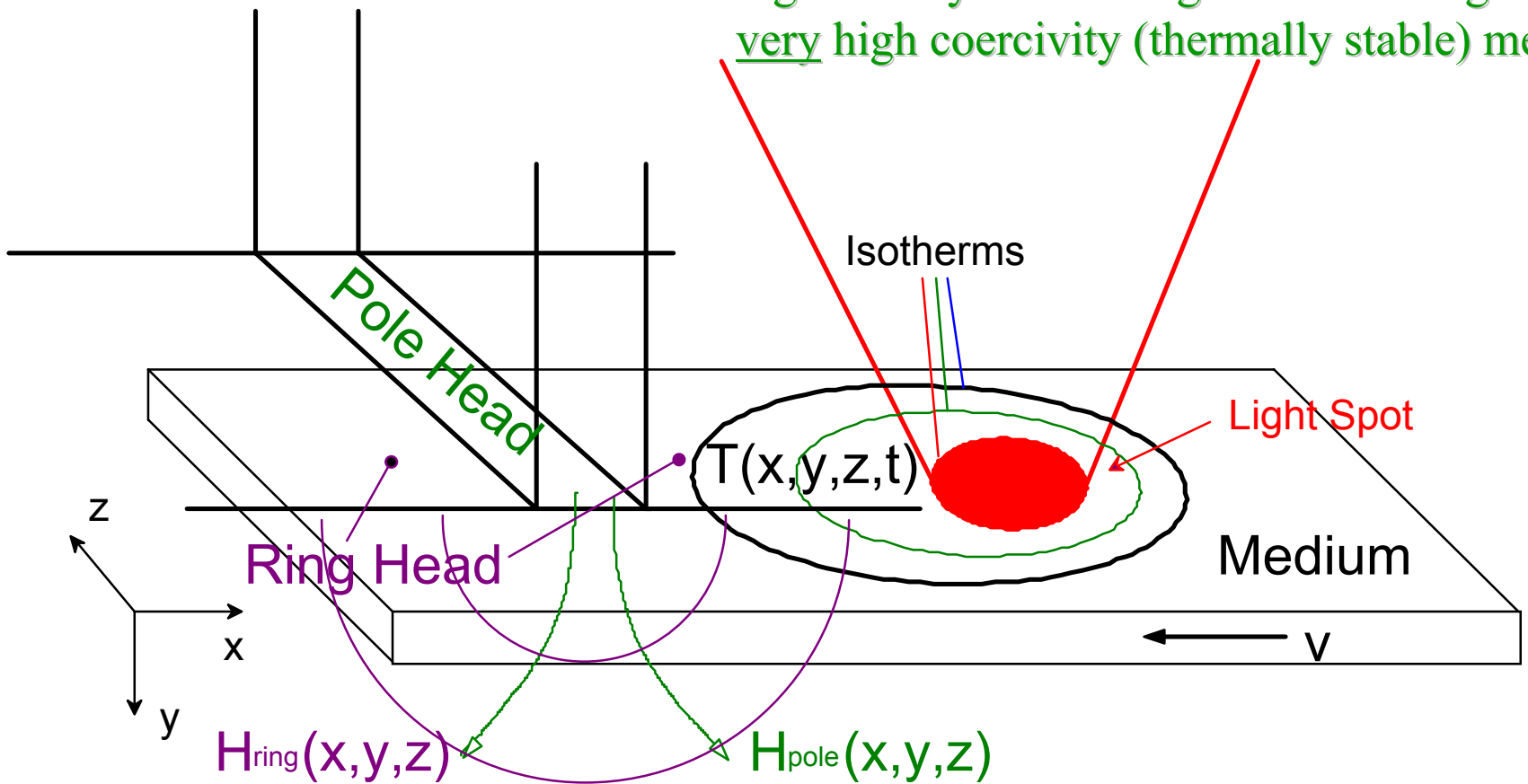
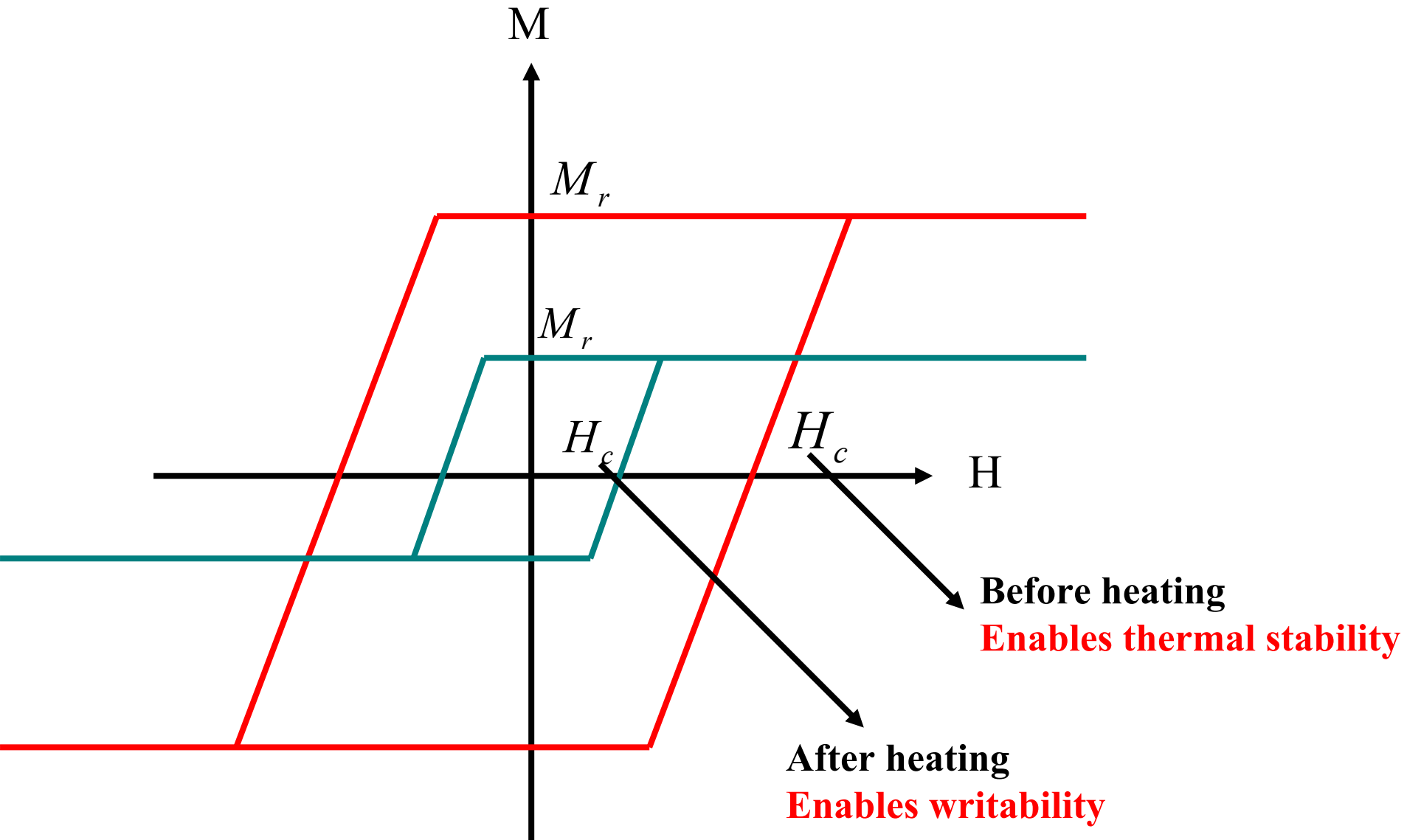
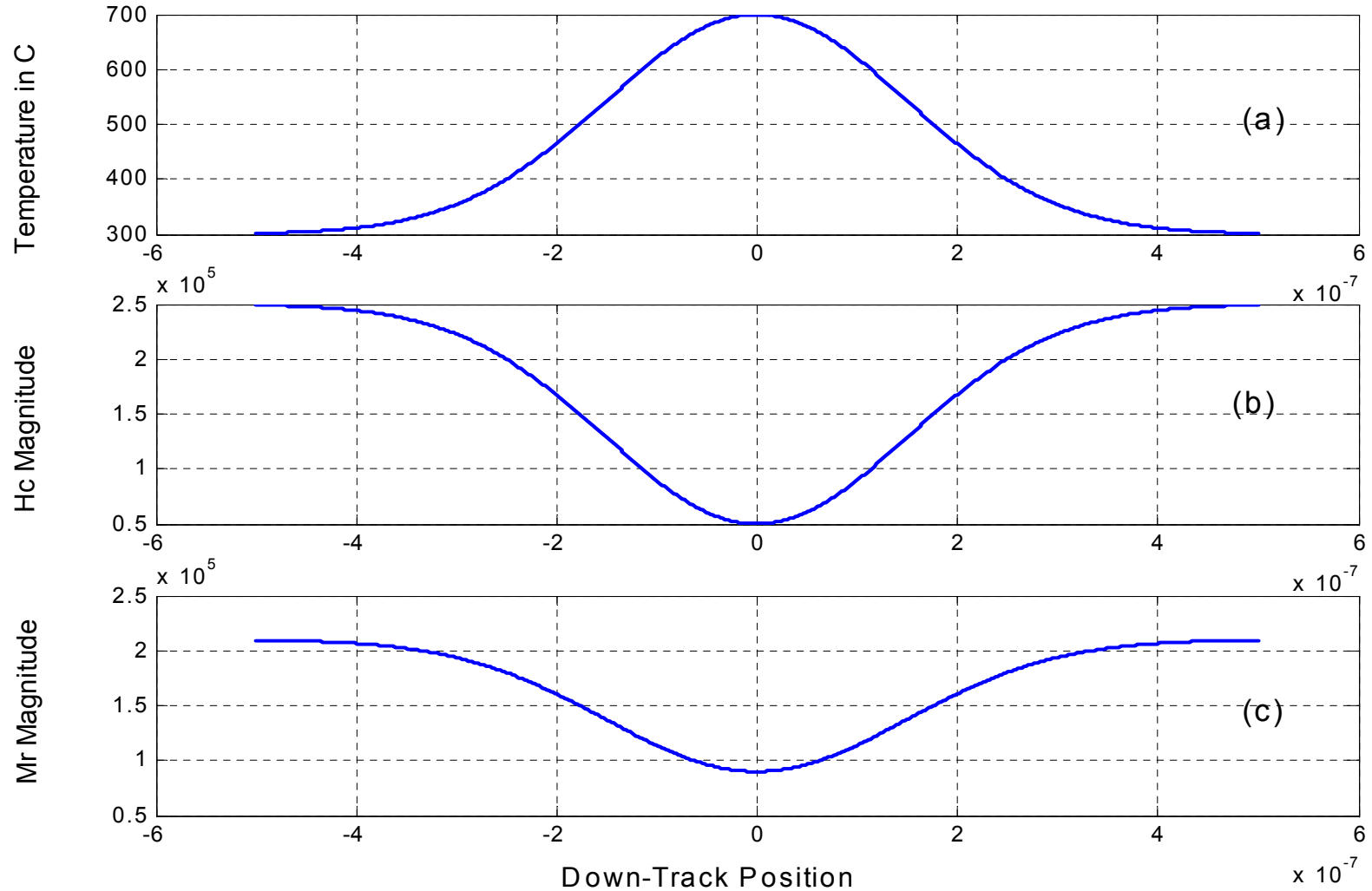


Image courtesy of T. McDaniel, Seagate Technology

Idea behind HAMR

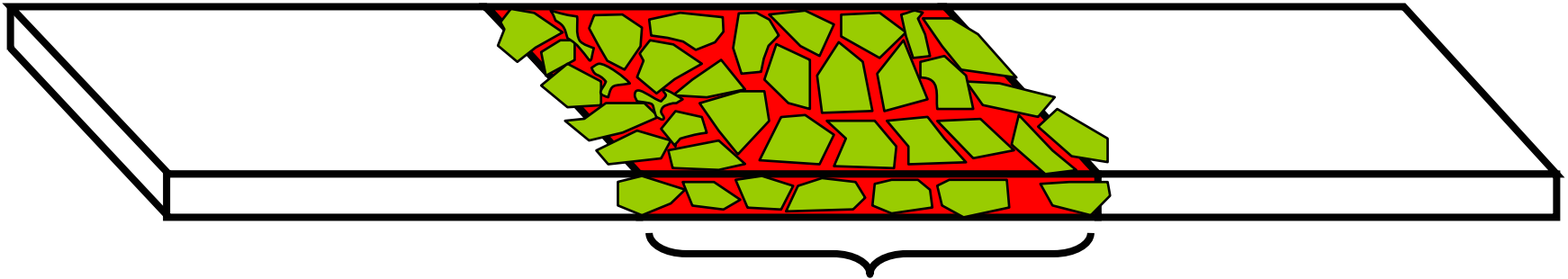


An illustrative example



Why should we have any issue?

Assume speed to be 25m/s



25 nm equivalent to 1ns

- Increase the heat of the medium by 300K – 400K
- Write the bit of information
- Cool the medium

!!! Complete everything in 1ns !!!

Major issues in HAMR

- Magnetic issues
 - Availability of desirable $K_u(T)$ for particles
 - Controllability of the spatial orientation of $K_u(T)$ to minimize the temperature difference
- Thermal issues
 - Lubricant and overcoat stability
 - Air bearing flying stability
 - Media-Head air bearing surface smoothness
- Optical issues -- Confining light in a very small spot. Some methods
 - Solid Immersion Lenses (SIL)
 - Apertures
 - Antennas
 - Waveguides

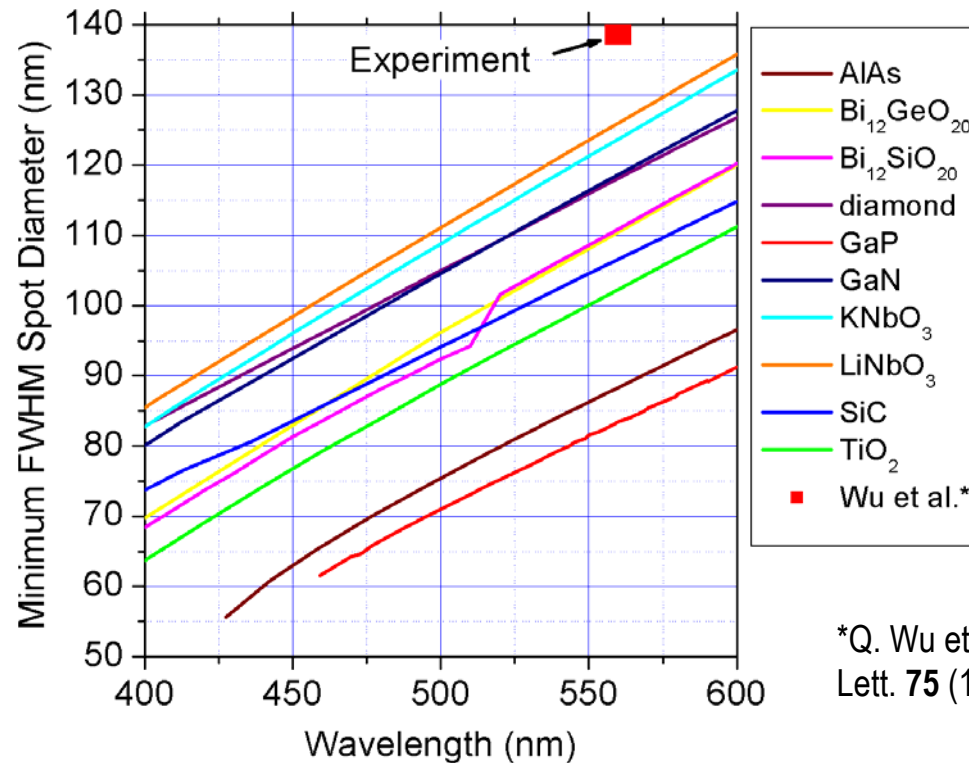
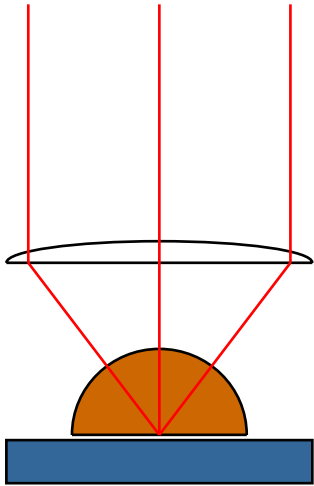
Each have their own advantages and disadvantages (*)

(*) Challener et al,
Jpn. J. Appl. Phys. 42, (2003) 981

Solid Immersion Lenses (SIL)

Theoretical spot size

$$\text{FWHM diameter: } d \geq \frac{0.51 \cdot \lambda}{n}$$



*Q. Wu et al., Appl. Phys. Lett. **75** (1999) 4064.

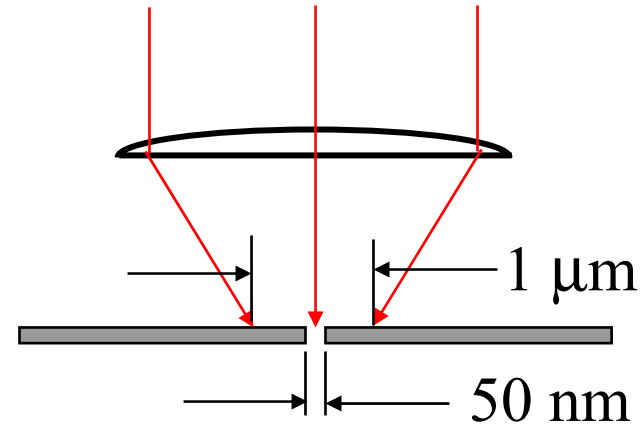
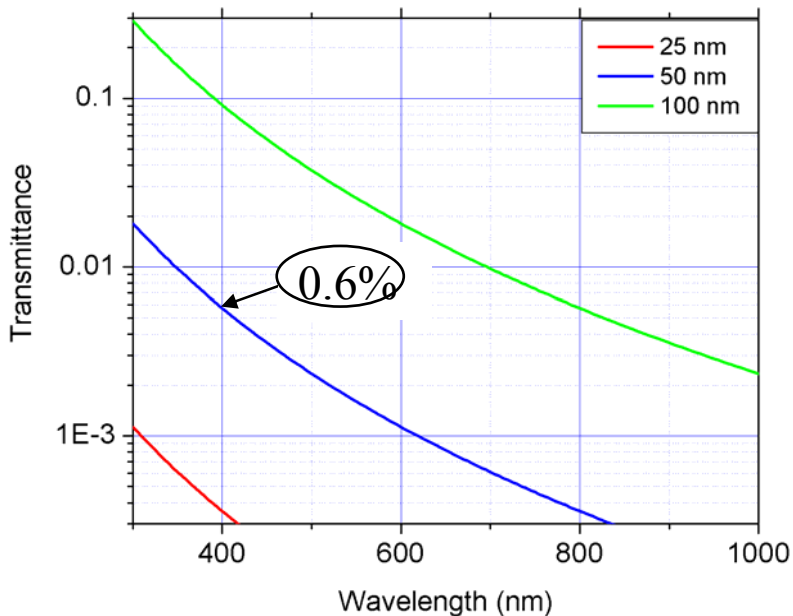
Image courtesy of T. McDaniel, Seagate Technology

Circular Aperture in Ideal Conductor

$$T = \left(\frac{64\pi^2}{27} \right) \cdot \left(\frac{d}{\lambda} \right)^4 \equiv \frac{\left[\frac{\text{transmitted power}}{\text{area}} \right]_{\text{hole}}}{\left[\frac{\text{incident power}}{\text{area}} \right]_{\text{plane wave}}}$$

Hans Bethe,
Phys. Rev.
 (1944) 163.

Transmittance of Holes in an Ideal Conductor



$$T \cdot \frac{A_{\text{hole}}}{A_{\text{spot}}} = 1.5 \times 10^{-5}$$

Image courtesy of T. McDaniel, Seagate Technology

How can we get a useful channel model?

$$M = F_{loop}(H_a)$$

$$H_a = H_h + H_d$$

$$H_x = \frac{H_0}{\pi} \left[\tan^{-1} \left(\frac{x + g/2}{y} \right) - \tan^{-1} \left(\frac{x - g/2}{y} \right) \right]$$

$$H_y = -\frac{H_0}{2\pi} \ln \frac{(x + g/2)^2 + y^2}{(x - g/2)^2 + y^2}$$

Karlqvist Head Field Approximation

$$H_d = \frac{\partial M}{\partial x} * H_x^{step}(x)$$

Function of M

Very difficult to solve loop equation

Approximation – Thermal Williams Comstock Model

Williams Comstock equation

$$\frac{\partial M}{\partial x} = \frac{\partial M}{\partial H} \left[\frac{\partial H_h}{\partial x} + \frac{\partial H_d}{\partial x} \right]$$

Thermal Williams Comstock equation

$$\frac{\partial M}{\partial x} = \frac{\partial M}{\partial H} \left[\frac{\partial H_h}{\partial x} + \frac{\partial H_d}{\partial x} - \frac{H_h + H_d}{H_c} \frac{\partial H_c}{\partial T} \frac{\partial T}{\partial x} \right]$$

Temperature profile



Temperature dependent



Using the equations

Find transition location x_0 which satisfies

$$H_h(x_0) + H_d(x_0) = H_c(x_0)$$

Find a-parameter as a function of x_0

$$a = \textit{Function}(x_0, \dots, \dots, \dots)$$

Isolated transition response

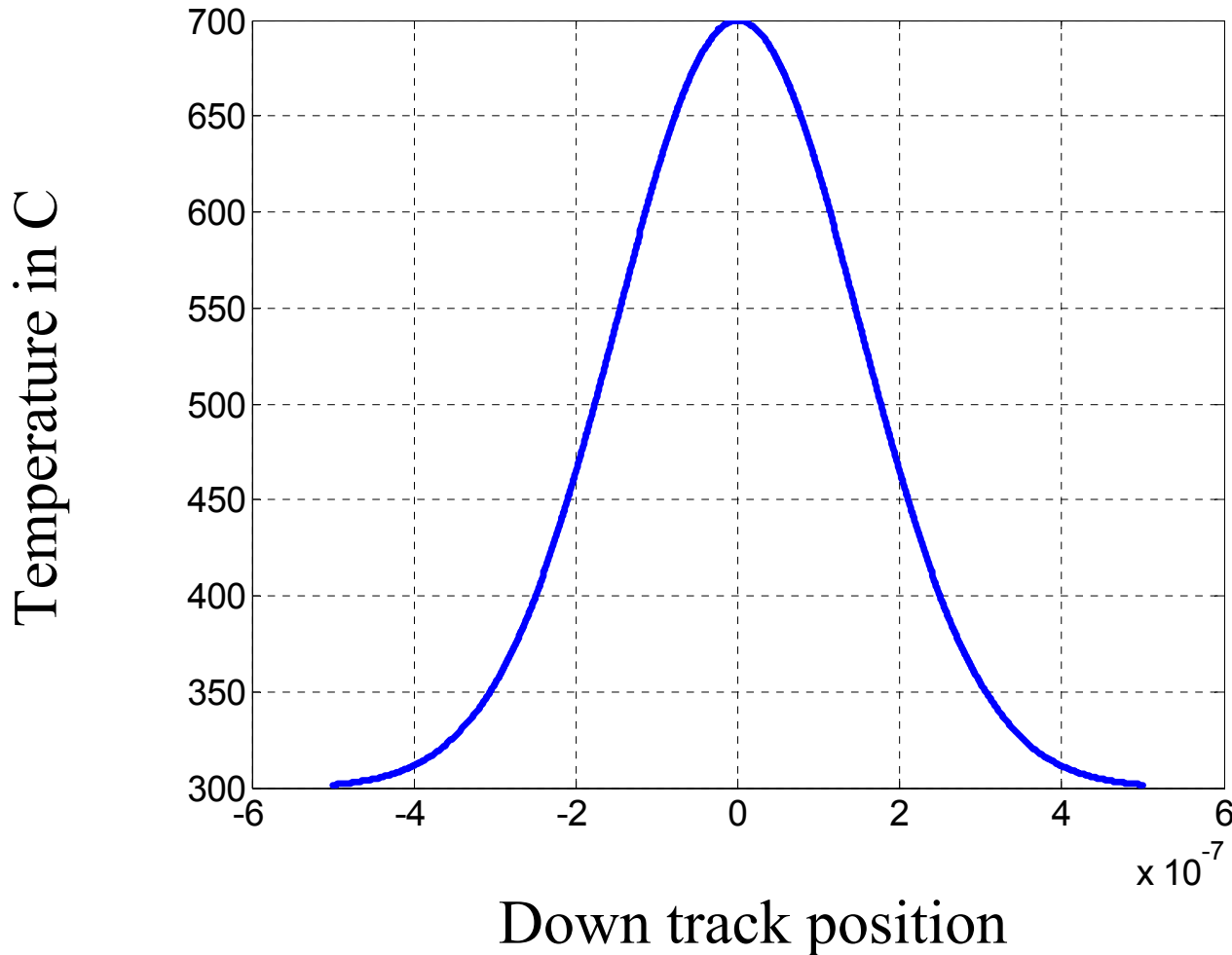
Readback voltage from isolated transition

$$V_{GMR}(x) = CM_x(x_0) \delta \left(\tan^{-1} \frac{x + g/2}{a(x_0) + d} - \tan^{-1} \frac{x - g/2}{a(x_0) + d} \right)$$

Temperature dependent

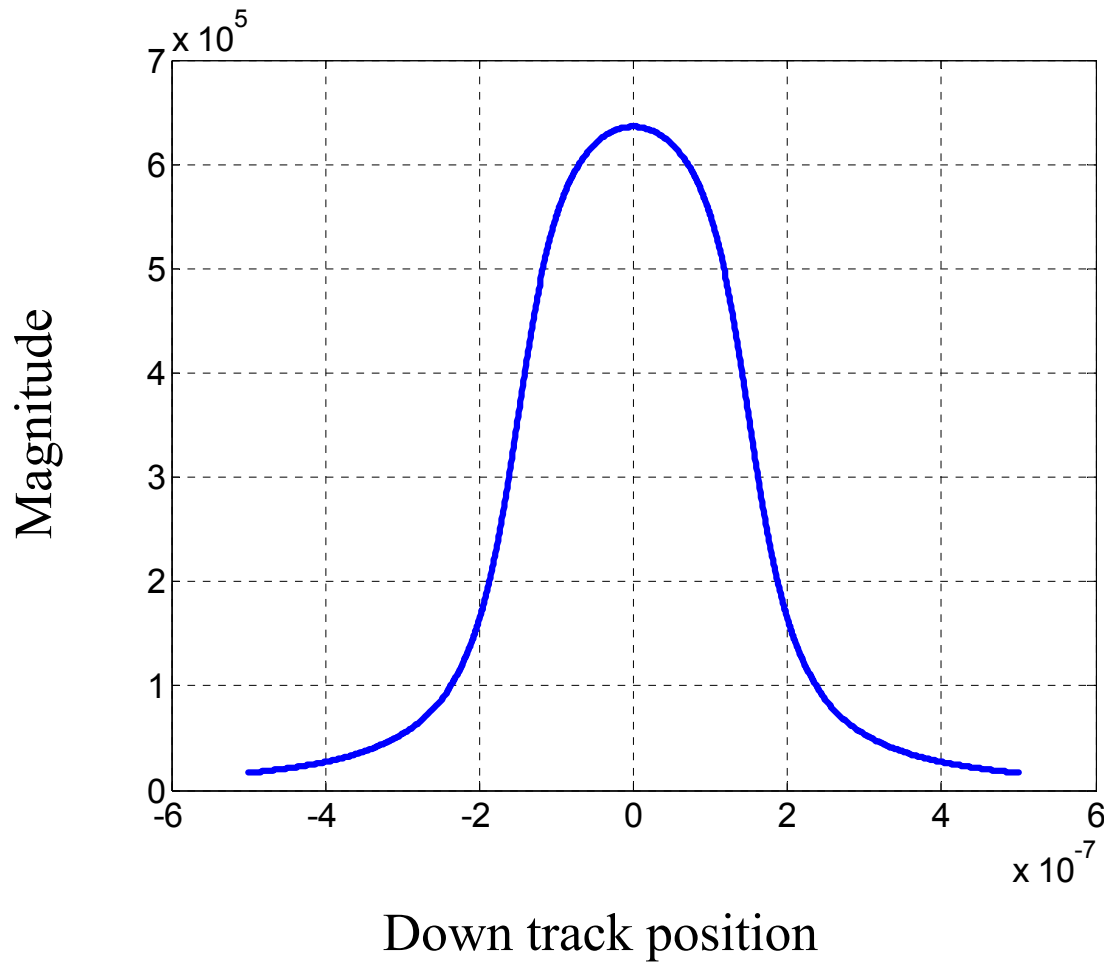
Requires iterations to find a parameter and x_0
for given temperature profile

Temperature profile as a function of position



Peak Temp = 700
Temp sigma = 150 nm

Longitudinal Component of Karlqvist Head Field as a function of position



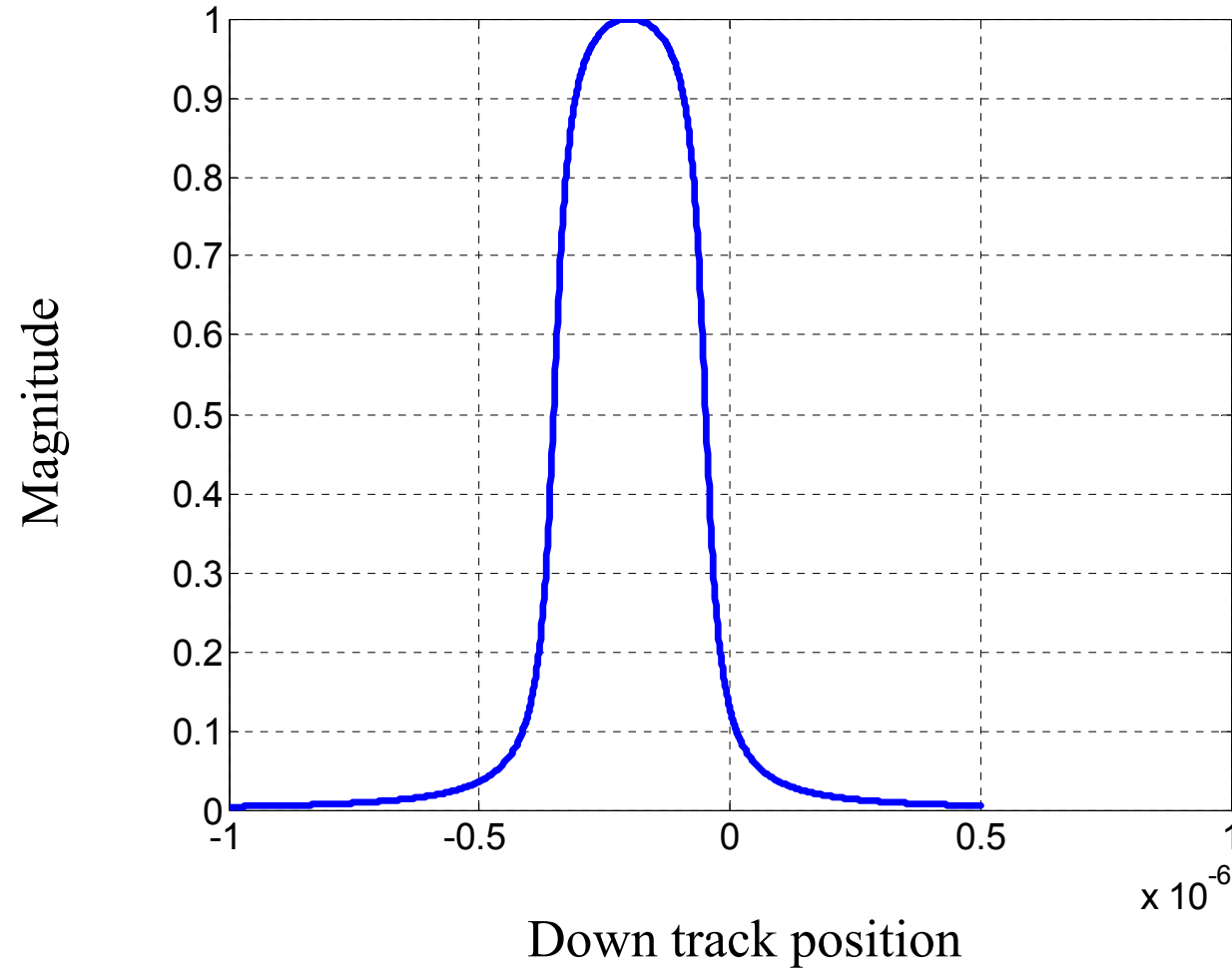
$$H_x = \frac{H_0}{\pi} \left[\tan^{-1} \left(\frac{x + g/2}{y} \right) - \tan^{-1} \left(\frac{x - g/2}{y} \right) \right]$$

$$H_0 = 800000 \text{ A/m}$$

$$g = 300 \text{ nm}$$

$$y = 50 \text{ nm}$$

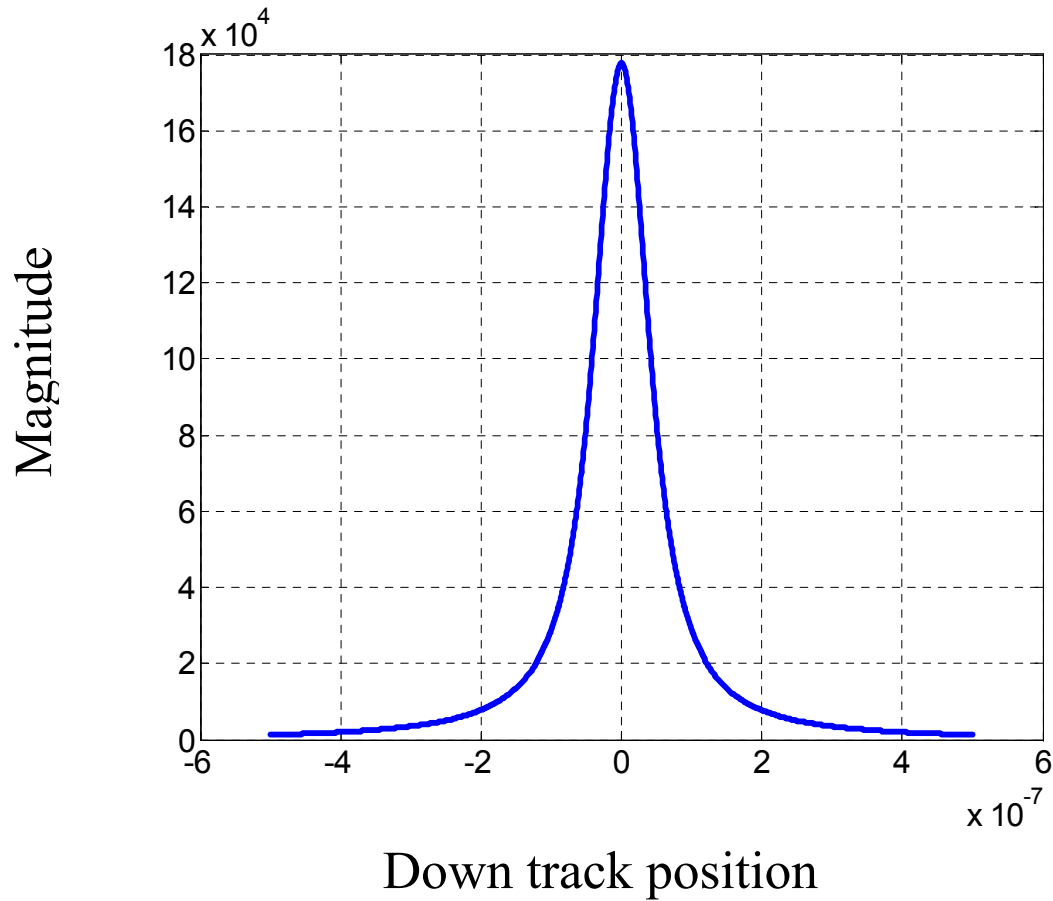
Normalized isolated transition response as a function of position



a_parameter = 22.8nm

x_0 = -200nm

Another Head Field as a function of position



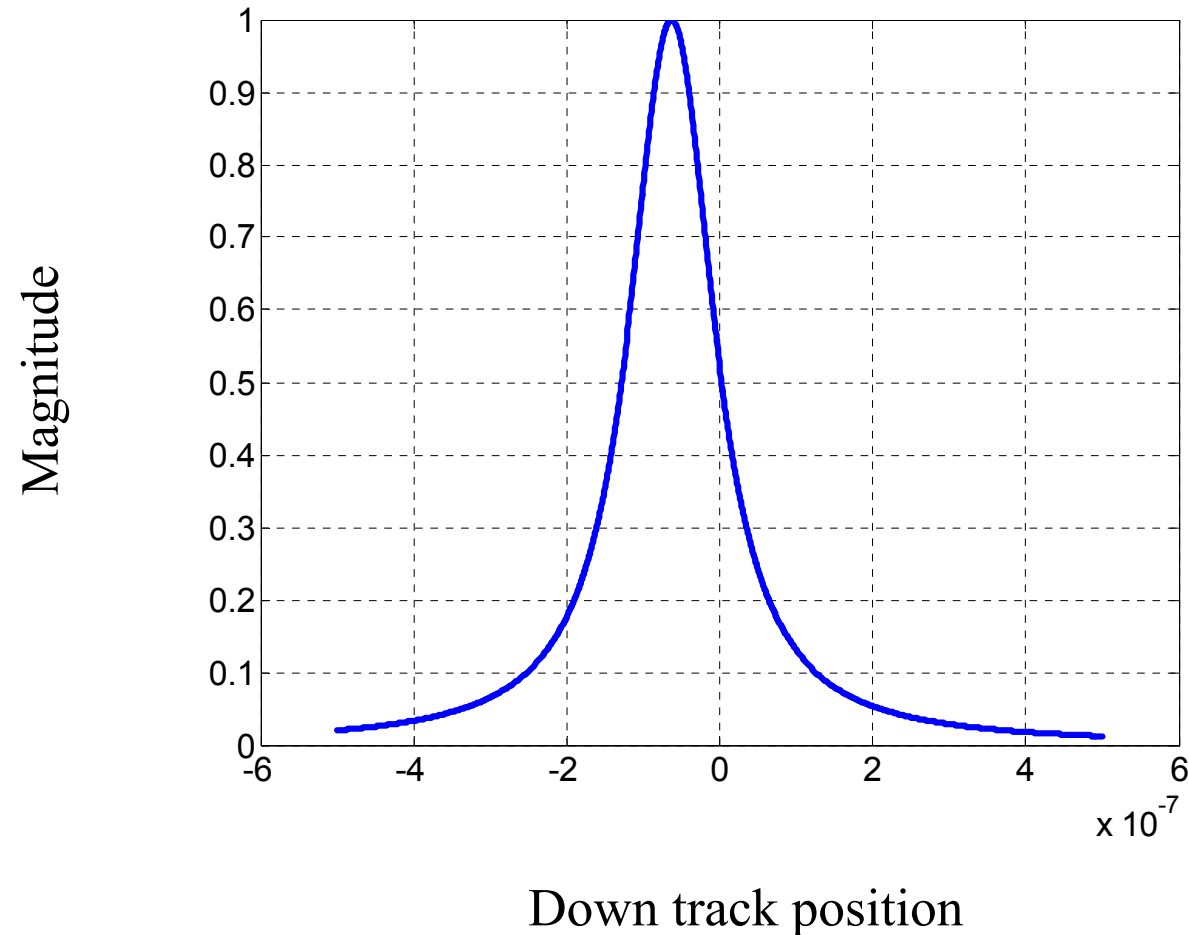
$$H_x = \frac{H_0}{\pi} \left[\tan^{-1} \left(\frac{x+g/2}{y} \right) - \tan^{-1} \left(\frac{x-g/2}{y} \right) \right]$$

$$H_0 = 500000 \text{ A/m}$$

$$g = 50 \text{ nm}$$

$$y = 40 \text{ nm}$$

Normalized isolated transition response as a function of position



A_parameter = 20.6nm

X_0 = -63nm

System should be considered as a whole

- Joint optimization of
 - Tribological system
 - Medium magnetics
 - Near field optical system

Necessary to solve the issues

- Success in optimization will determine the attainable areal density

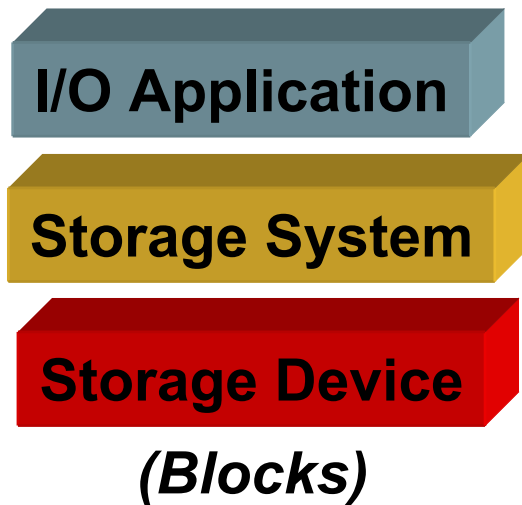
A decorative graphic on the left side of the slide, featuring a dark background with blurred, glowing blue and white binary code (0s and 1s) arranged in horizontal lines, suggesting digital data or storage.

Object Based Storage Devices

Storage Architectures Today

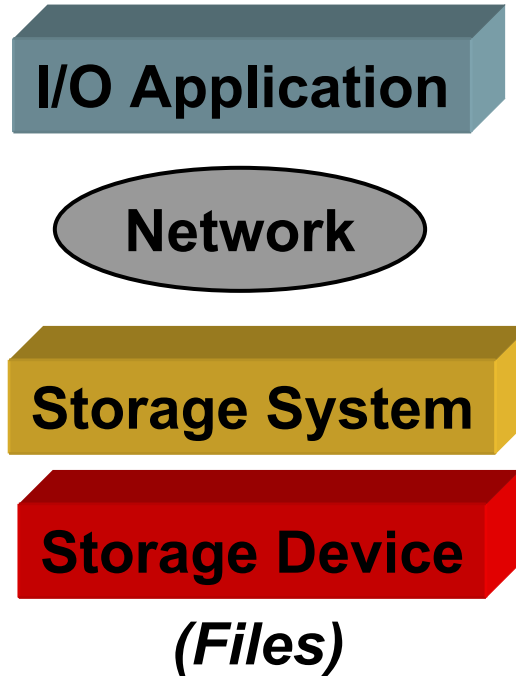
Goal: Scalability, Security, Data Sharing

Direct Attached Storage (DAS)



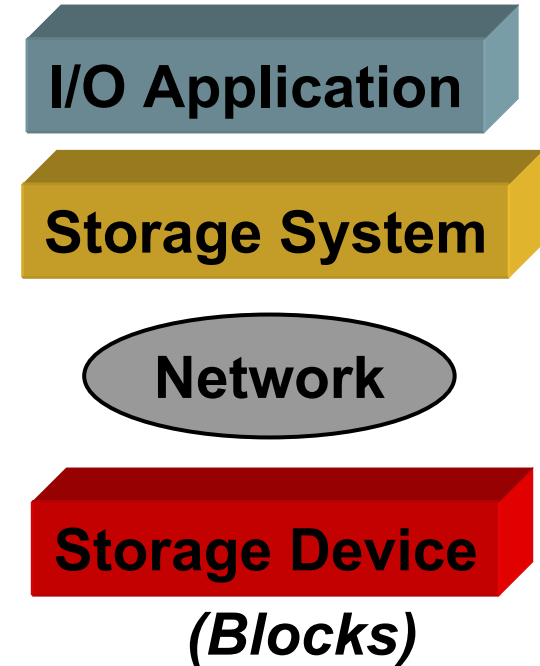
- Pros:** Simple, Physically secure
- Cons:** Not scalable, no data sharing, limited capacity sharing

Network Attached Storage (NAS)



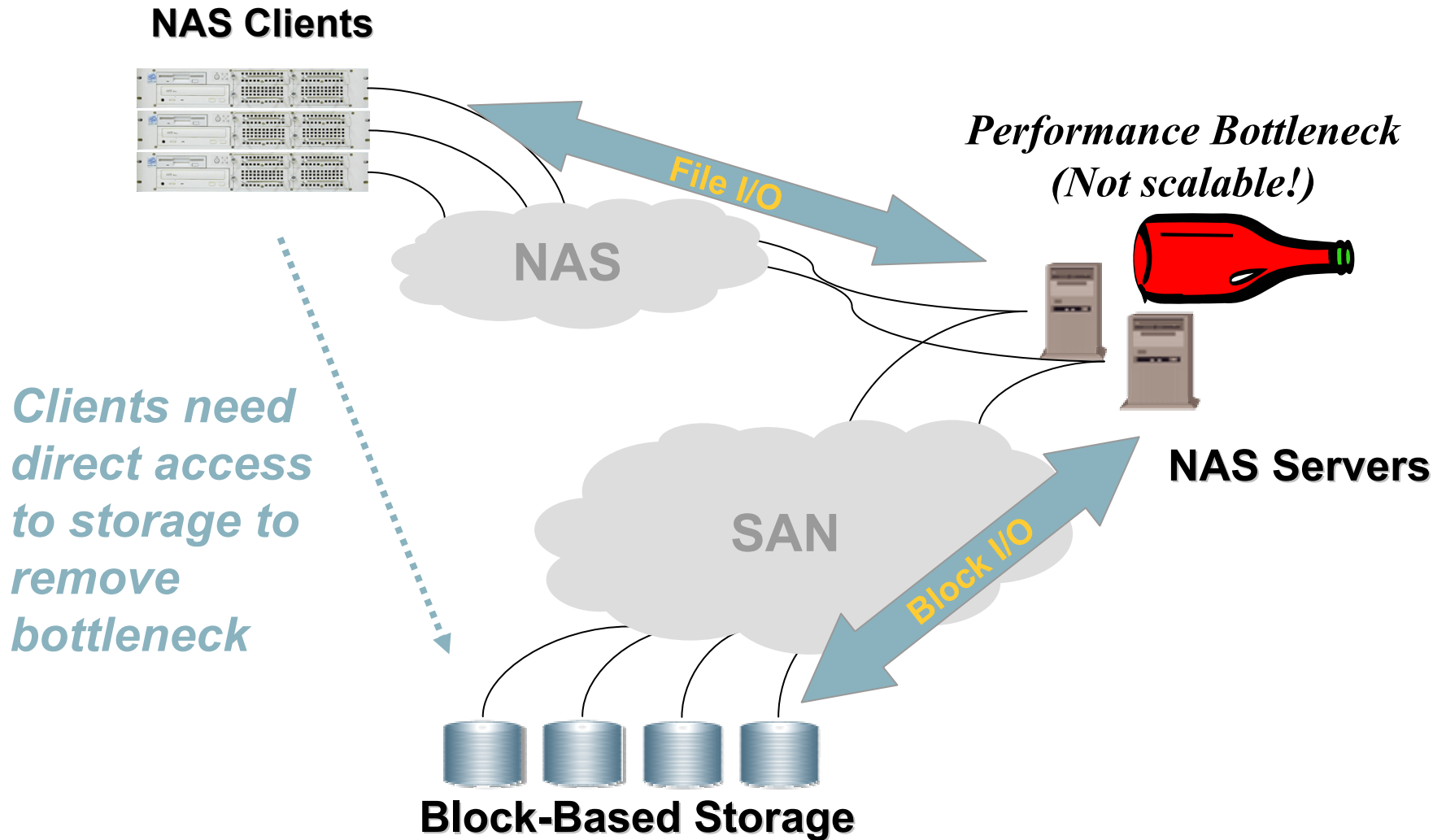
- Pros:** Secure data and capacity sharing
- Cons:** Limited scalability

Storage Area Network (SAN)



- Pros:** Scalable capacity sharing
- Cons:** No data sharing

Today's File Server



2nd Generation File Server

SAN/FS Clients

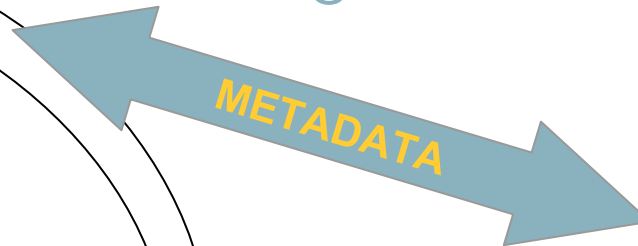
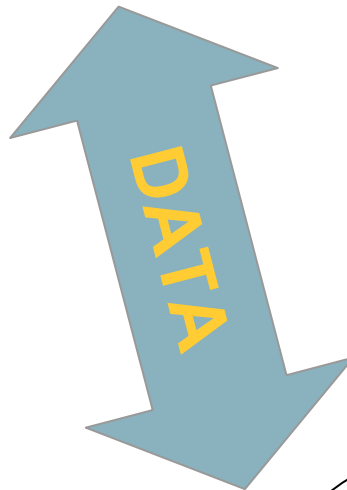


*Scalable, but
poor security!*

SAN/FS Servers

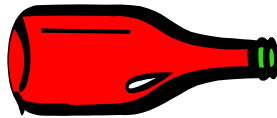


Trusted SAN

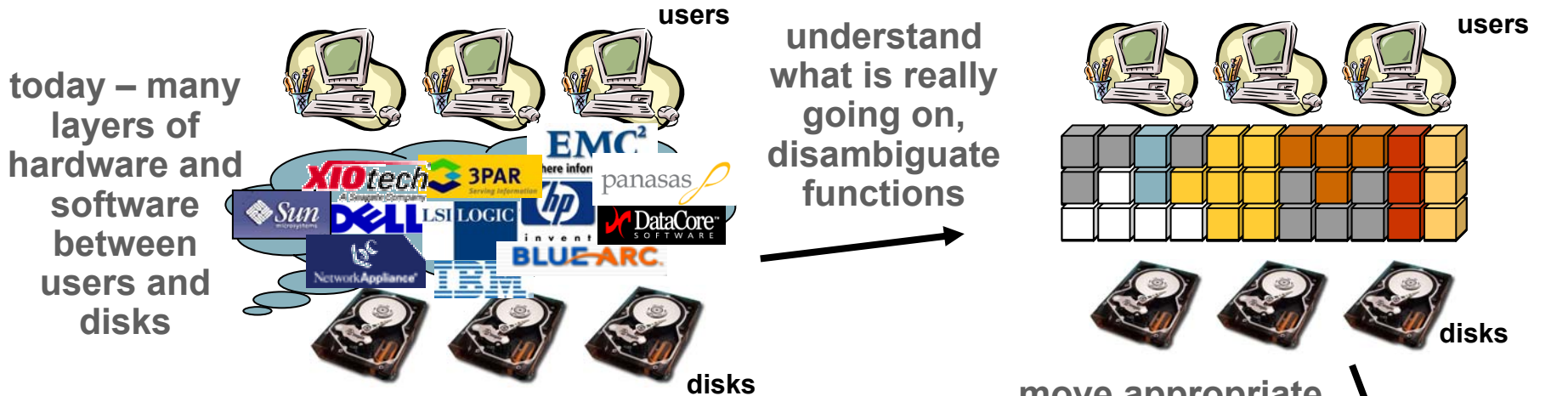


Block-Based Storage

*-Security is poor
-High virtualization
overhead*



The Problem – expand endpoint function



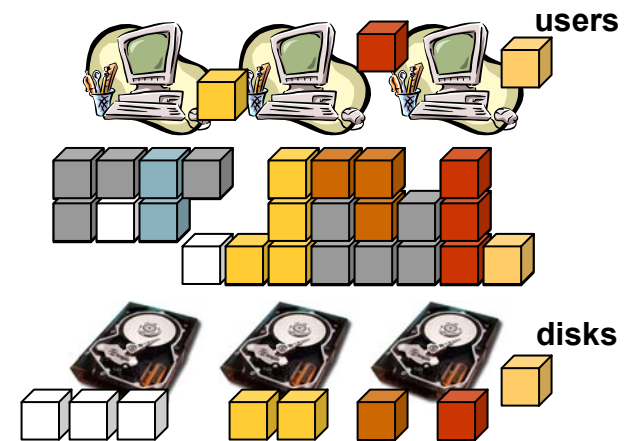
Endpoints (users at top, disks at bottom)

- not very sophisticated today
- disks don't understand users/apps
- users/apps don't understand disks
- need many intermediaries to translate

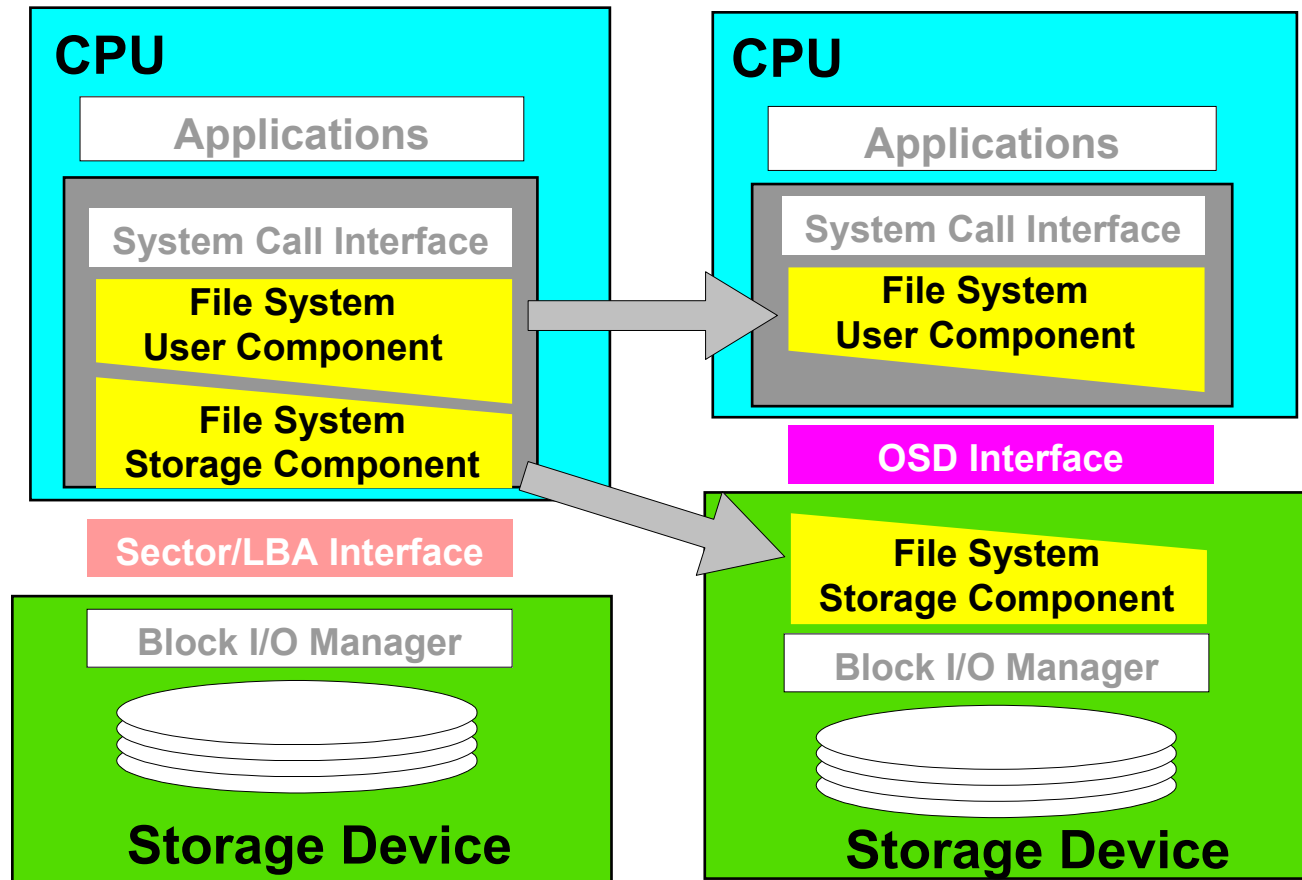
Intermediary functions

- some add value (e.g. data sharing)
- others simply cover limitations (e.g. reliability via RAID)

move appropriate functions to the endpoints



OSD Interface



OSD Functions

Basic Protocol

- READ
 - WRITE
 - CREATE
 - REMOVE
 - GET ATTR
 - SET ATTR
- } **Very Basic**
- } **Space Mgmt**
- } **Attributes**
- timestamps
 - vendor-specific
 - shared, opaque

Specialized

- APPEND – write w/o offset
- CREATE & WRITE – save msg
- FLUSH OBJ – force to media
- LIST – recovery of objects

Security

- Authorization – on each request
 - Integrity – for args & data
 - SET KEY
 - SET MASTER KEY
- } **shared secrets**

Groups

- CREATE COLLECTION
- REMOVE COLLECTION
- LIST COLLECTION

Management

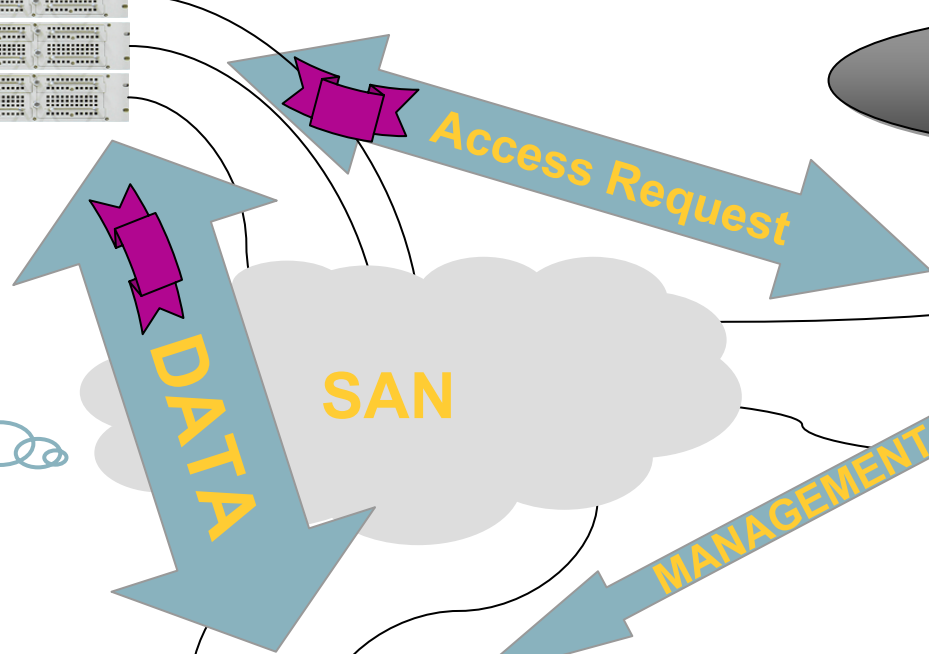
- FORMAT OSD
- CREATE PARTITION
- REMOVE PARTITION

File Server with OSD

Clients



Problem solved!

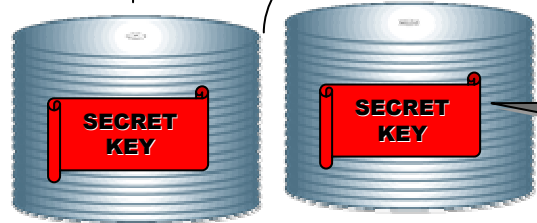


Check permissions



Servers

- Intelligent Device**
- Space Management
- Backup/Recovery
- QoS via attributes
- Security
- etc.

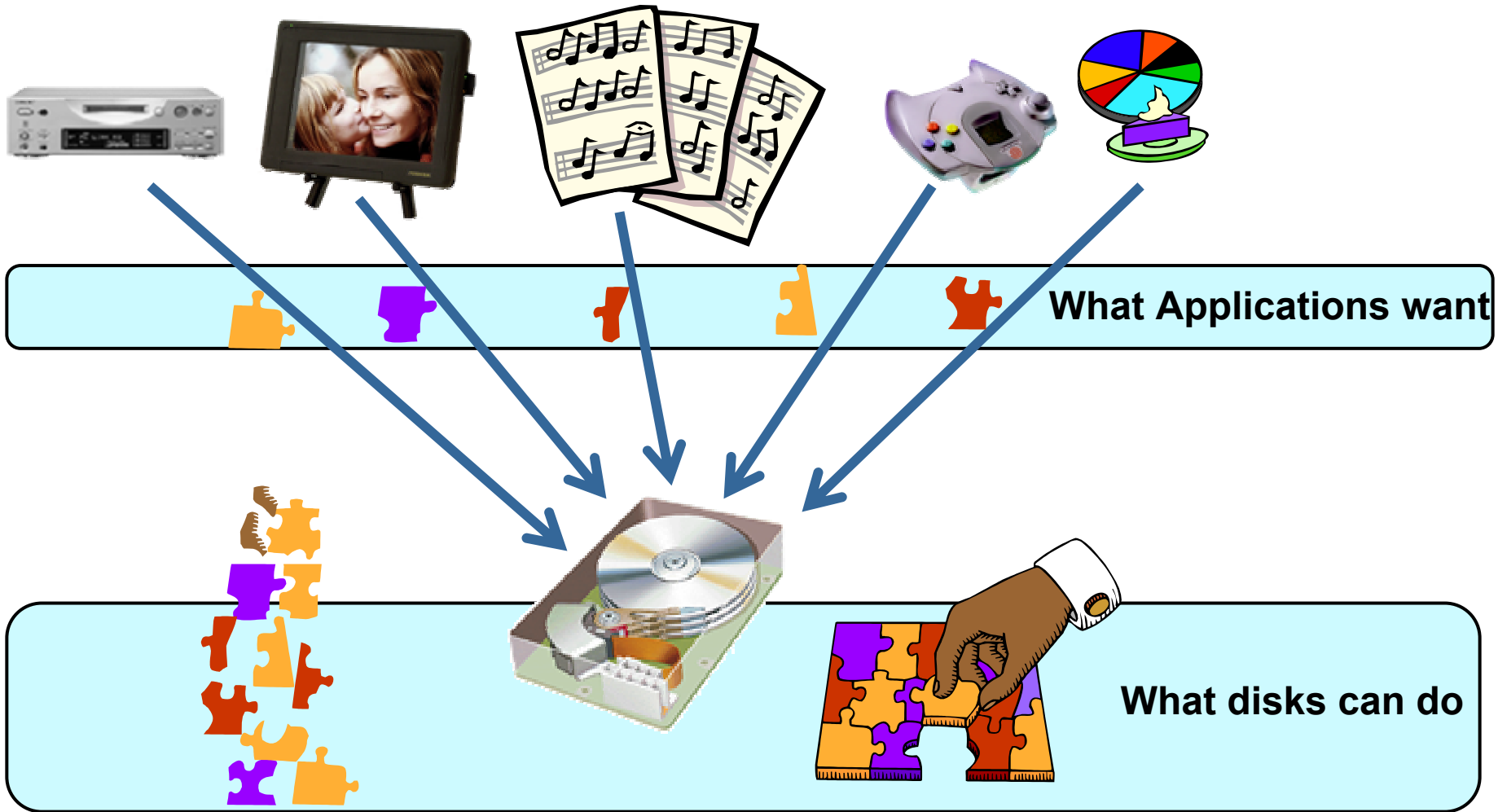


MANAGEMENT

Validate Capability

Object-Based Storage Device

Quality of Service on the Disk



Traditional

OSD

Example OSD Drive Uses

–Enterprise

- Data sharing
- Scalability
- Security
- Improved reliability
- Self-managed, self-configured drives

– Desktops/Notebooks

- Automatic de-fragmentation
- Object semantics
- Free space management
- QoS

–Consumer Electronics

- Video streams
 - Video can tolerate occasional bit loss
 - Drive takes advantage of this to improve performance (e.g., skipping ECC on a read)



Summary

- OSD enables scalable and secure data sharing
 - Highly desirable in the enterprise market
- Pushes intelligence down to disks
 - Self-aware, self-managed, self-configured drives
 - Better communication between applications and drives (QoS)
 - Increased system performance
 - Disk level computations (searches, etc.)
- It is REAL and HERE